



# High Speed PCB Structures

# Governing Equations

1861  
No computers!

James Clerk Maxwell



## Maxwell Equations

$$\begin{aligned}\nabla \times \vec{E} &= -j\omega\mu\vec{H} \\ \nabla \times \vec{H} &= j\omega\epsilon\vec{E} + \vec{J} \\ \nabla \cdot (\epsilon\vec{E}) &= \rho \\ \nabla \cdot (\mu\vec{H}) &= 0\end{aligned}$$

## material interfaces

$$\begin{aligned}\vec{n} \times (\vec{E}_1 - \vec{E}_2) &= 0 \\ \vec{n} \cdot (\epsilon_1\vec{E}_1 - \epsilon_2\vec{E}_2) &= \rho_s \\ \vec{n} \times (\vec{H}_1 - \vec{H}_2) &= \vec{J}_s \\ \vec{n} \cdot (\mu_1\vec{H}_1 - \mu_2\vec{H}_2) &= 0\end{aligned}$$

## impedance surfaces

$$\vec{E}_t = Z_s \vec{H} \times \vec{n}$$

## Helmholtz Equation

$$\begin{aligned}\nabla \times \frac{1}{\mu} \nabla \times \vec{E} + \\ j\omega\sigma \vec{E} - \omega^2 \epsilon \vec{E} \\ = -j\omega \vec{J}\end{aligned}$$

## PEC

$$\begin{aligned}\vec{n} \times \vec{E} &= 0 \\ \vec{n} \cdot \epsilon \vec{E} &= 0\end{aligned}$$

## metal skin impedance

$$Z_s = \sqrt{\frac{j\omega\mu}{\sigma}}$$

## PMC

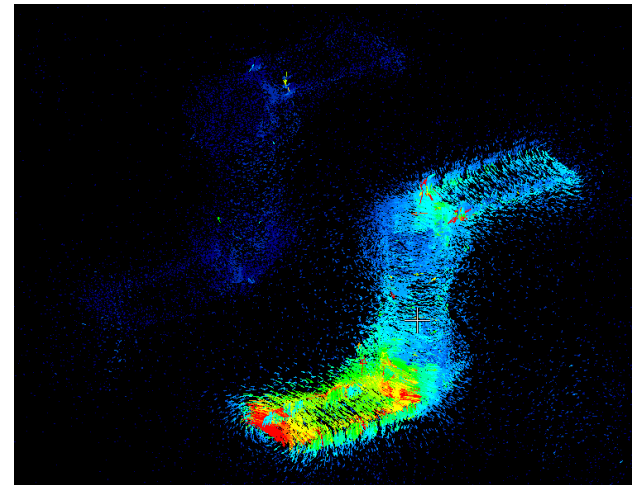
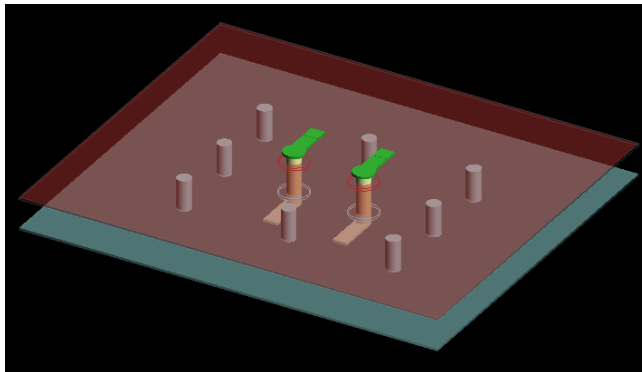
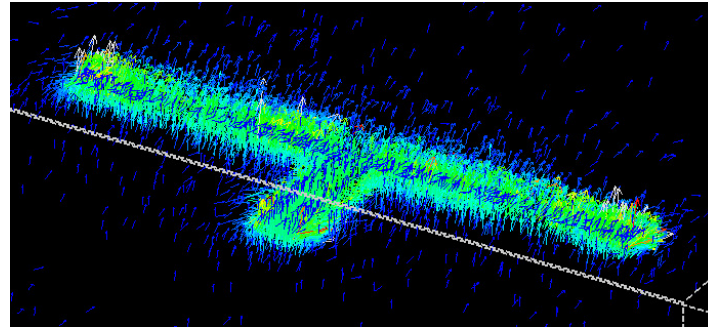
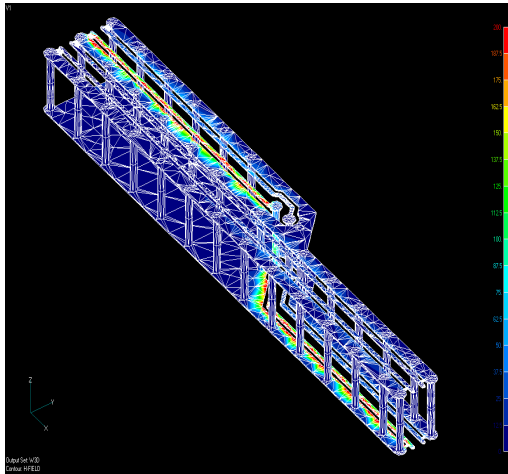
$$\begin{aligned}\vec{n} \times \vec{H} &= 0 \\ \vec{n} \cdot \mu \vec{H} &= 0\end{aligned}$$

## 1<sup>st</sup> order ABC

$$\vec{E}_t = \sqrt{\frac{\mu}{\epsilon}} \vec{H} \times \vec{n}$$

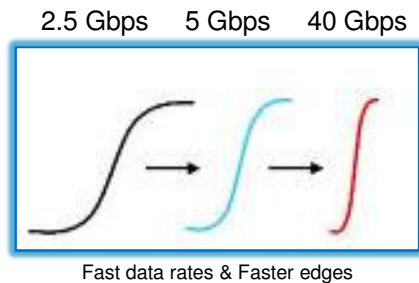
# Electromagnetic fields

- The signal or energy transferred is propagated as an electromagnetic wave.

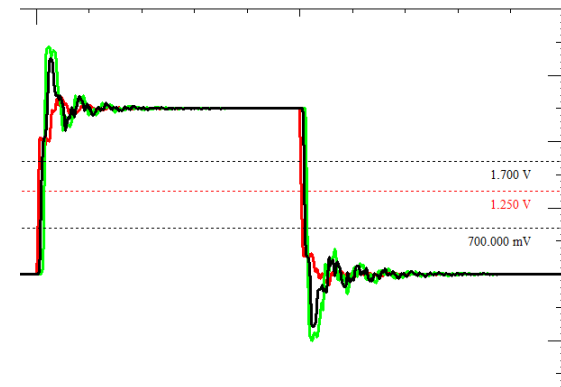


# Trend Today

- Ever increasing data rates; more high speed signal routing
- Signal quality issues arise: Reflection, loss, cross-talk
- High speed is the speed at which you need to worry about it
  - Sometimes as low as 1 G
- What is DDR4, 5 and serdes at today?
  - 1.2V to 1.4V 2G 5G 12G
- DDR4 now requires eye diagram analysis

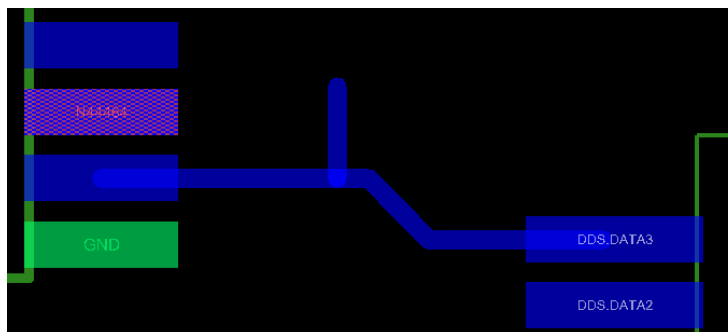
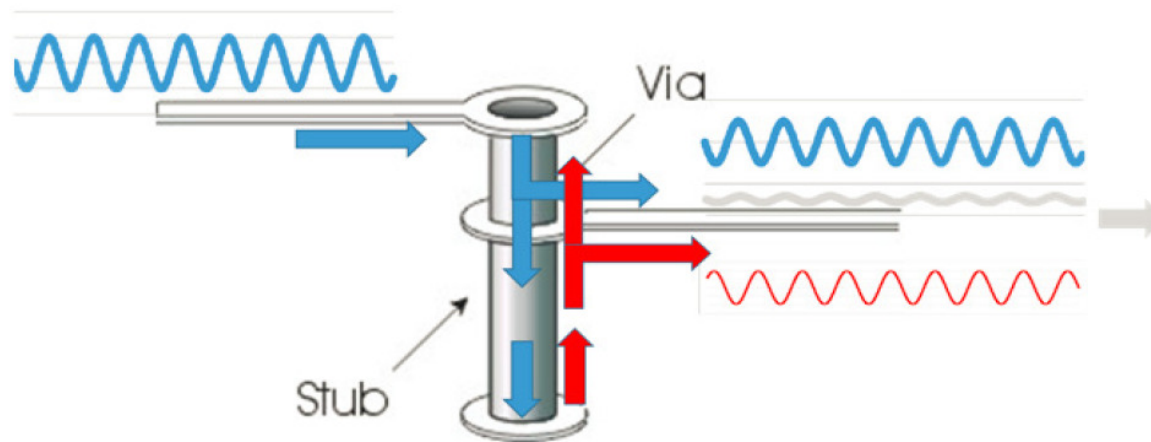


$$V = \frac{\Delta I}{\Delta T}$$



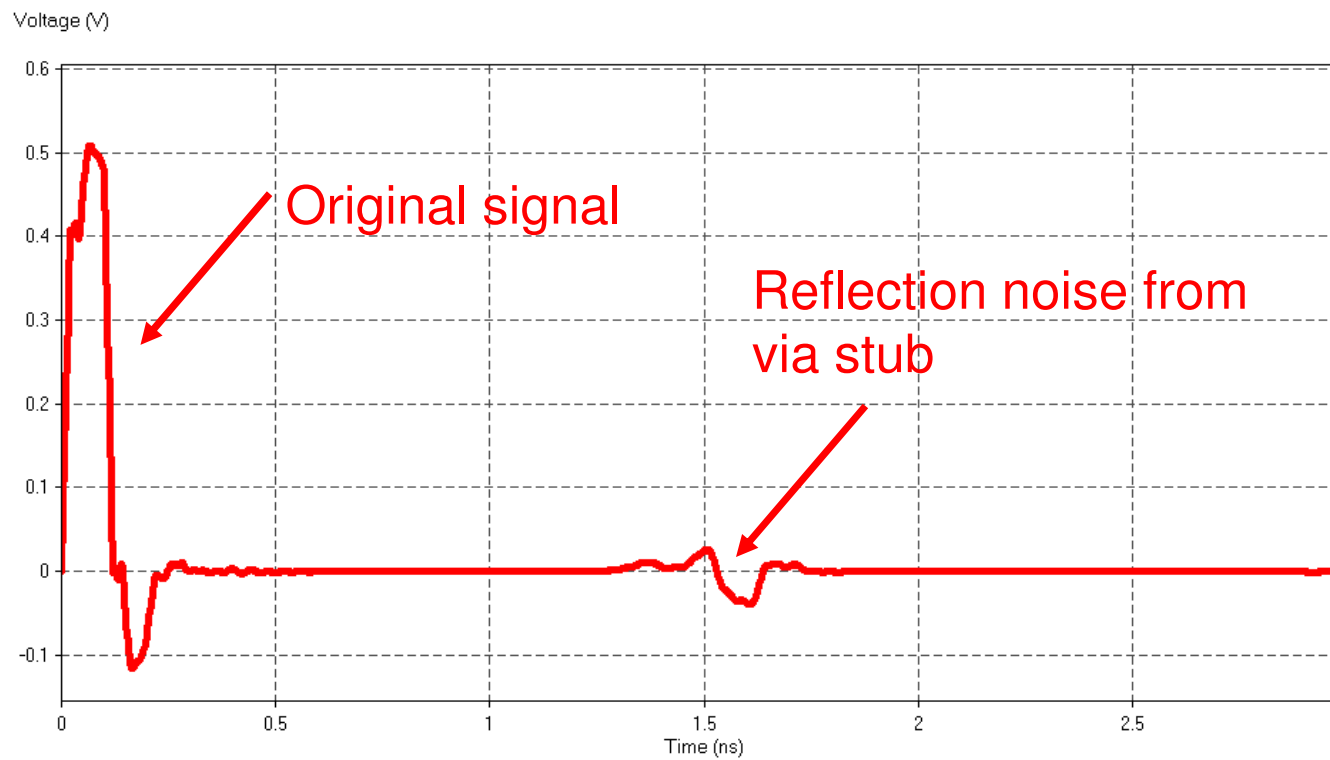
# Via Stubs effect on signals

When a signal is injected into a trace it travels until it reaches the junction of the via stub and the trace. The signal splits, some continues to the receiver while some continues to the bottom of the stub. At that point it reflects back up interfering with the original signal

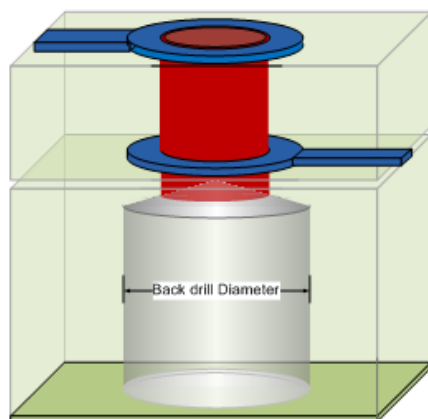


A Via Stub is electrically similar to a T in a routed trace

# Effect of a via stub in time



# Backdrill



Drilling the via stub away eliminates the reflection issues

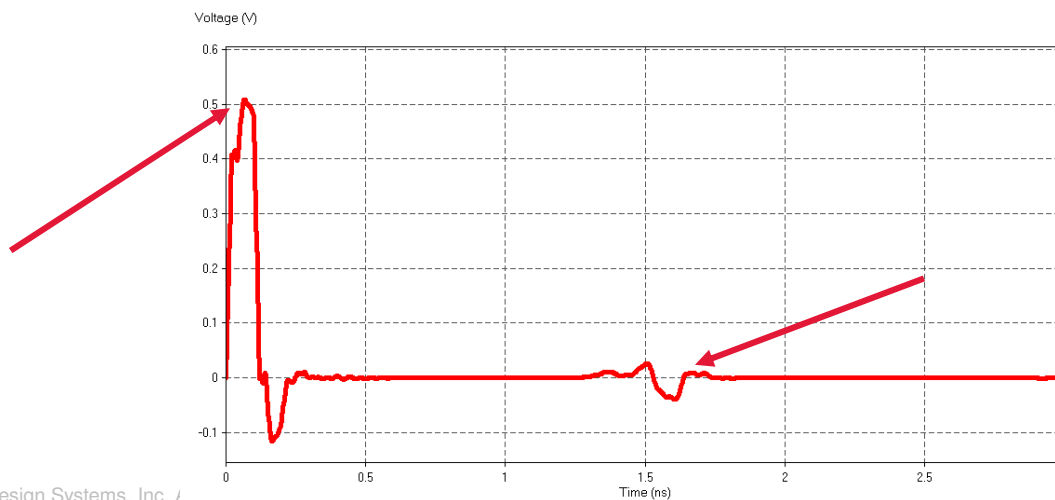
-More accurate high/low voltage

-Less ringing and noise

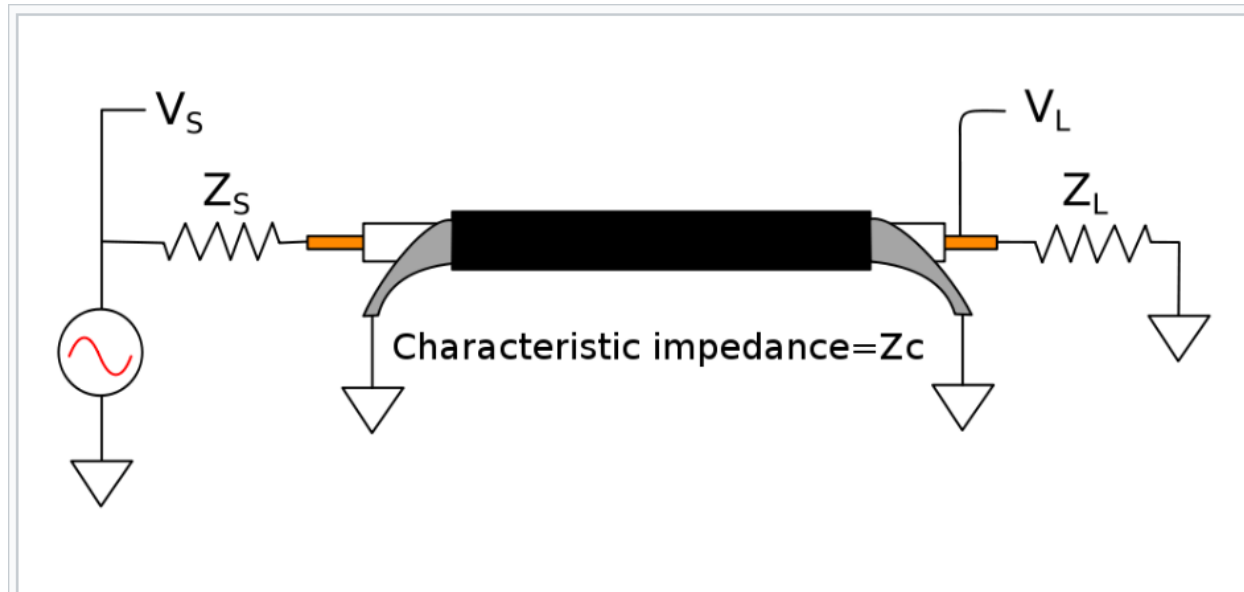
Do you need to backdrill every via?

No

It's a trade off between cost and performance



# Impedance

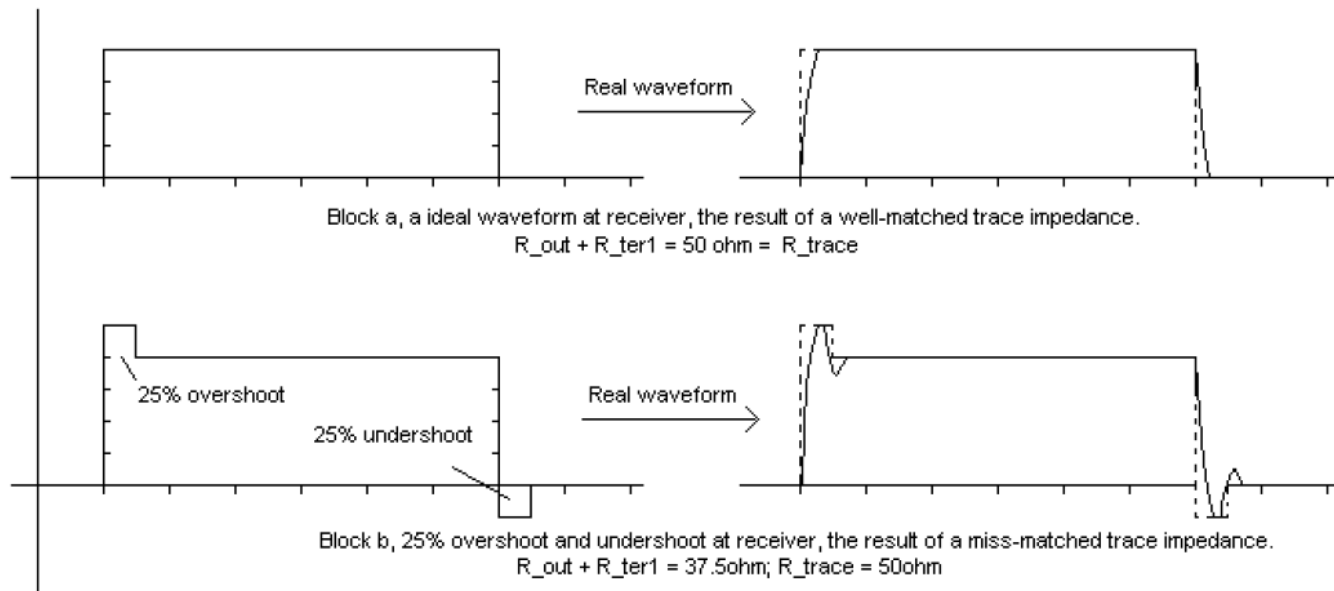


The purpose of a transmission line is to get the maximum amount of energy to the other end of the line (or to transmit information with minimal error), so the reflection is as small as possible. This is achieved by matching the impedances so that they are equal

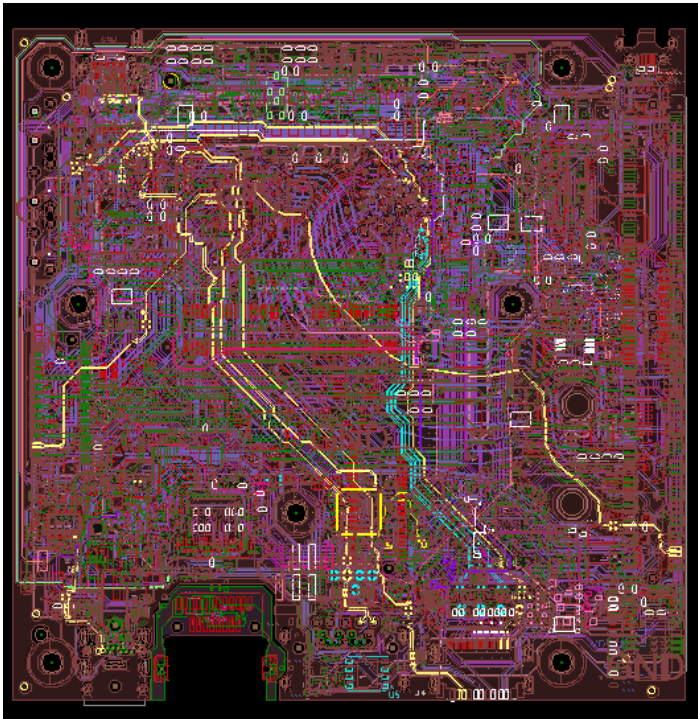


# Impedance

- Impedance discontinuities generate reflections.
- Reflections cause temporary ringing (voltage oscillations above and below the eventual steady-state level)



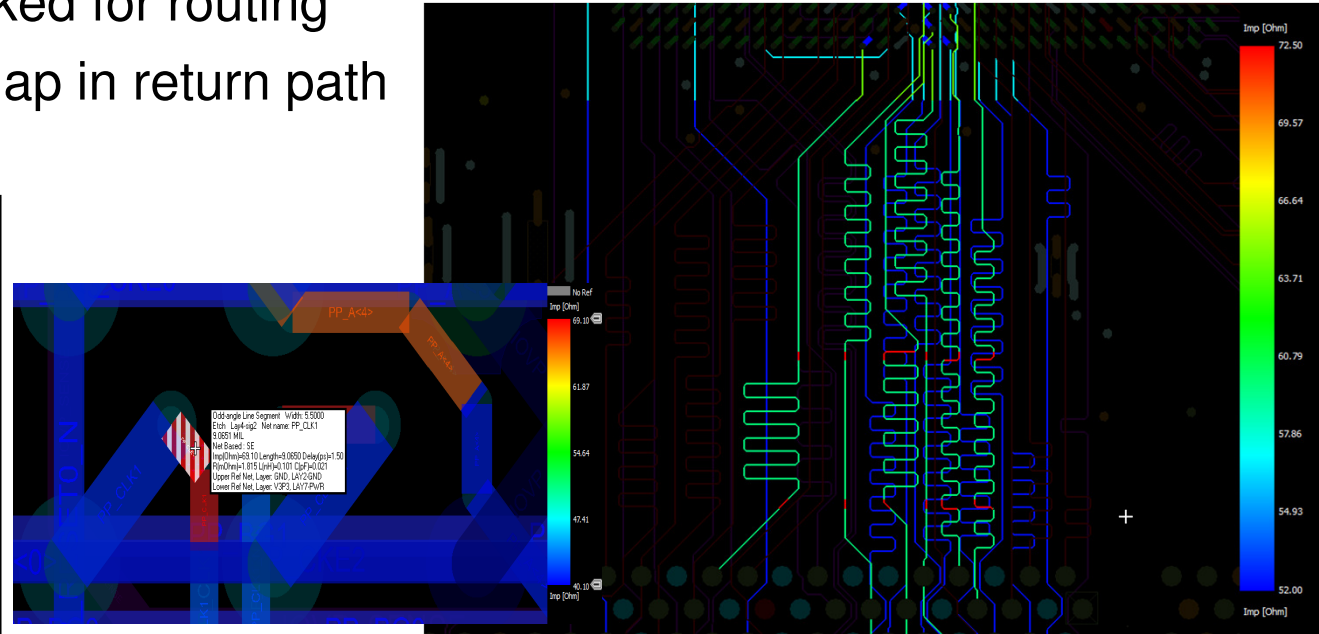
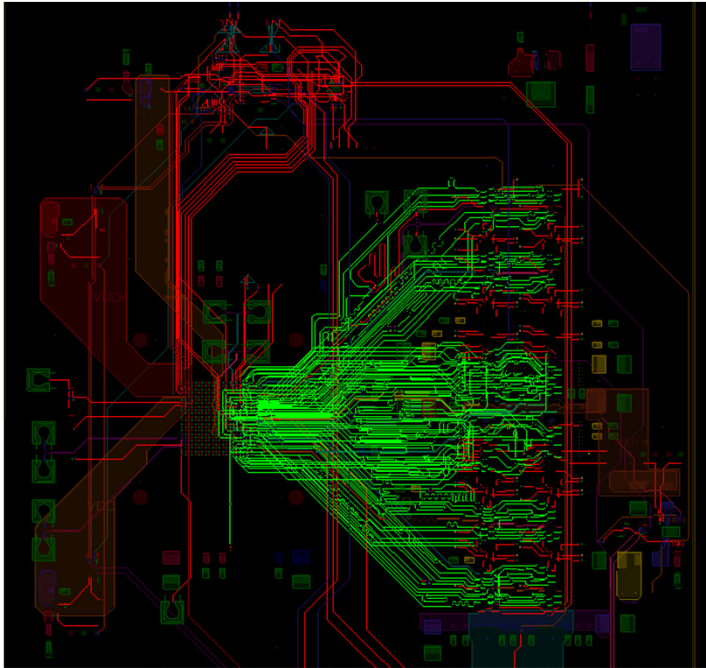
Where are the impedance problems?



Rules of thumb and line width rules may no longer cut it

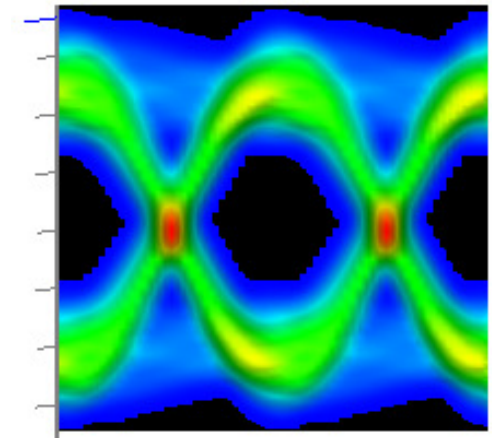
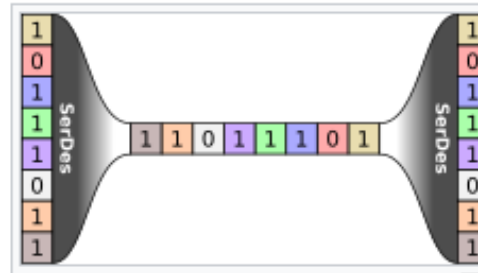
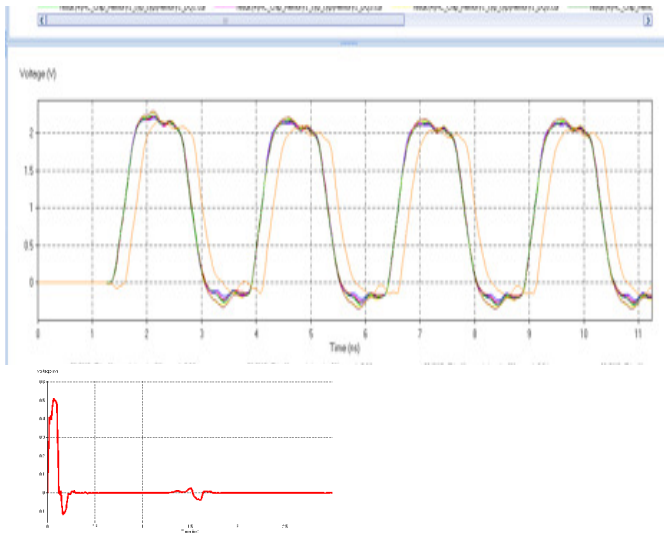
# Impedance discontinuities examples

- Major issues caused by stackup or line width change
- Hard to find segments tweaked for routing
- Impedance change due to gap in return path

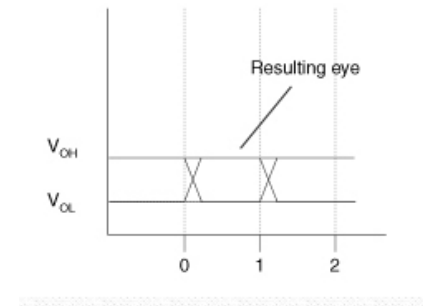
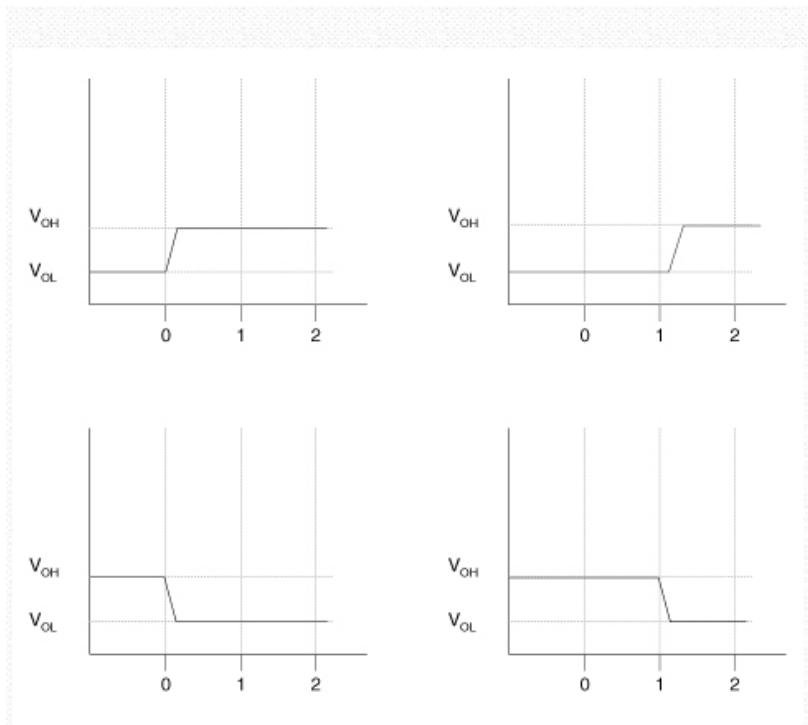


# What's an Eye Diagram

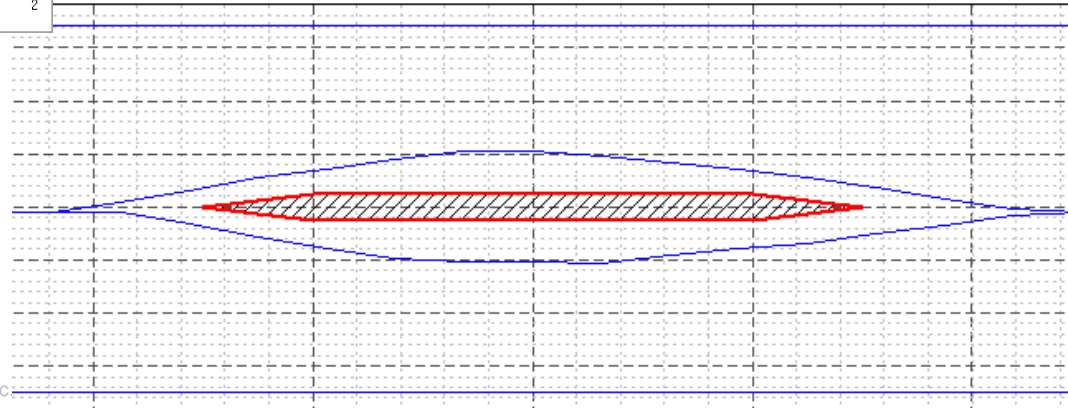
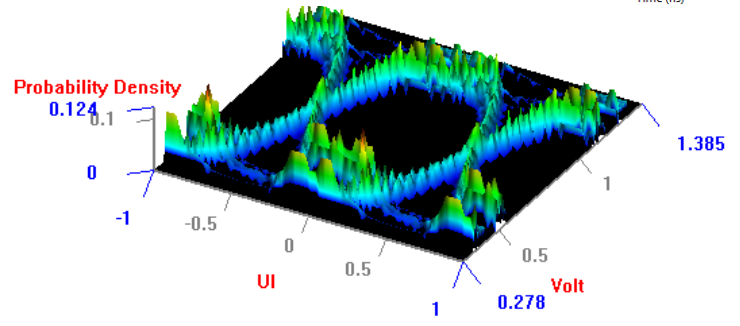
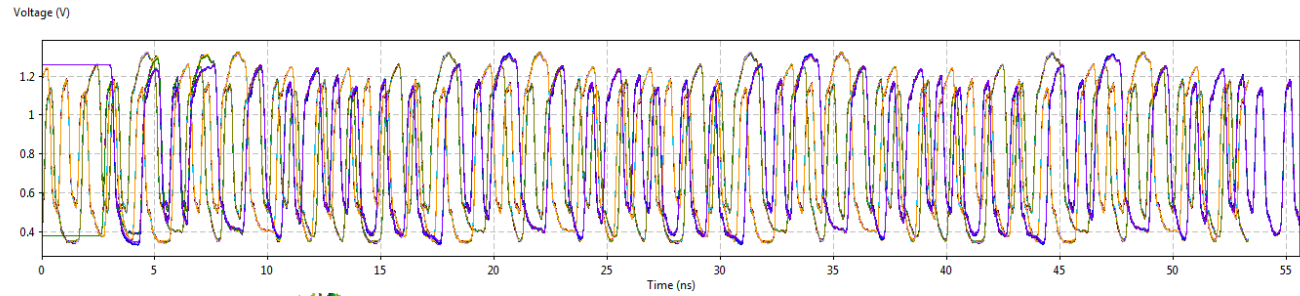
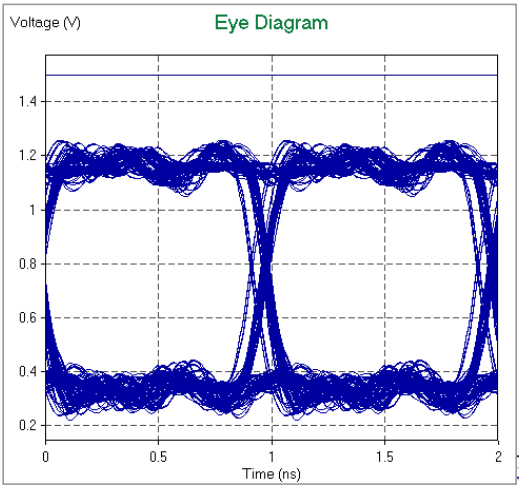
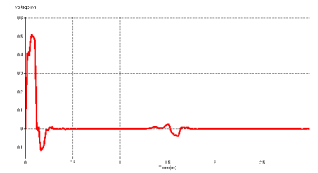
- High speed differential interfaces like DDR4 or PCIe carry billions of bits.
- An Eye diagram is a method to ensure every single one of those bits will be properly received
- A simulation is run, capturing the waveforms for each 0-1 and 1-0 transition.
- The waveforms are then super-imposed on top of each other
- The results look like eyes, the opening is the area where the signal is samples at the receiver



Bit sequences 011, 001, 100, and 110 are superimposed over one another to obtain the final eye diagram.



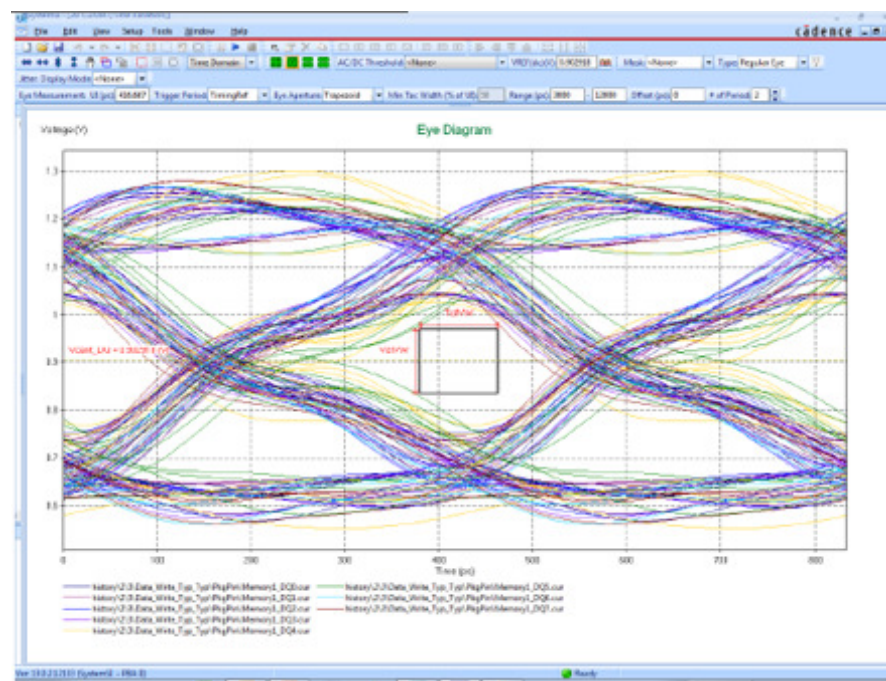
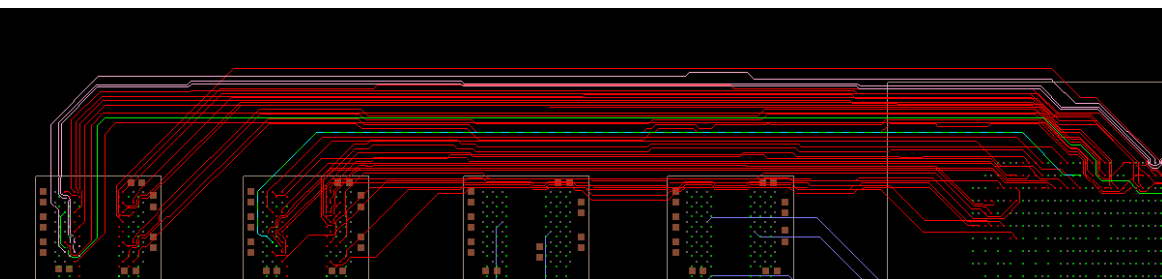
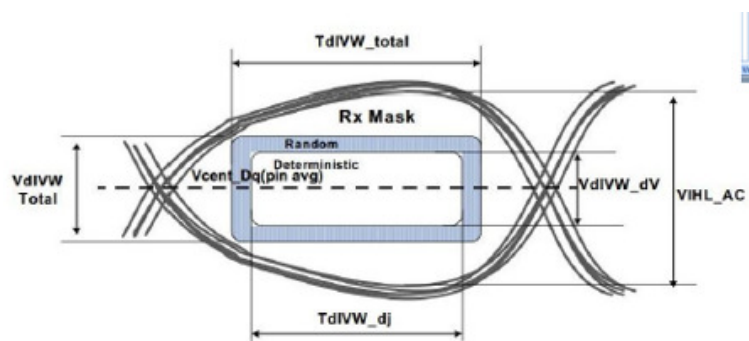
# What's an Eye Diagram



# DDR4 compliance

## How an Eye diagram is used

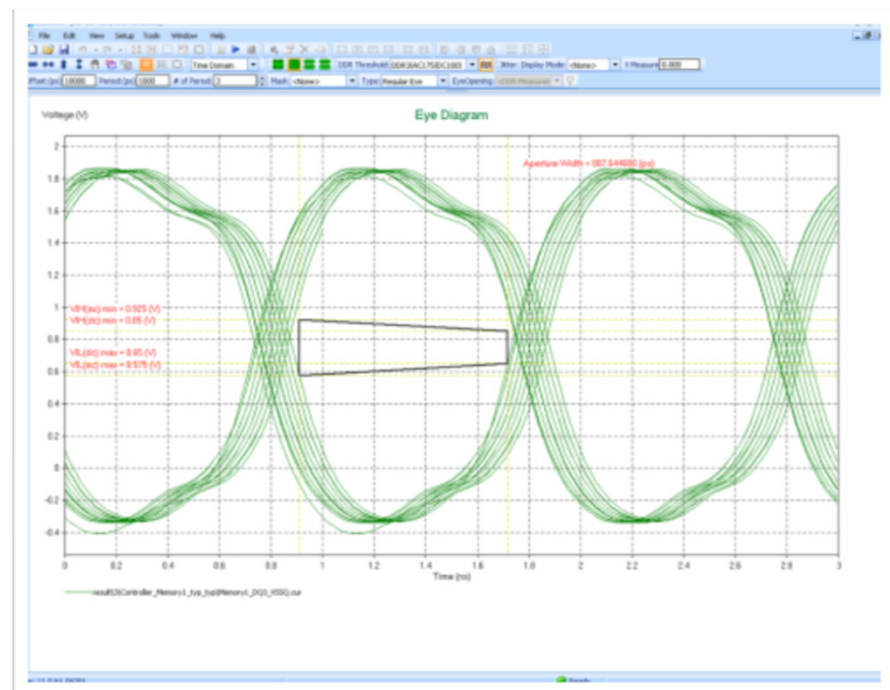
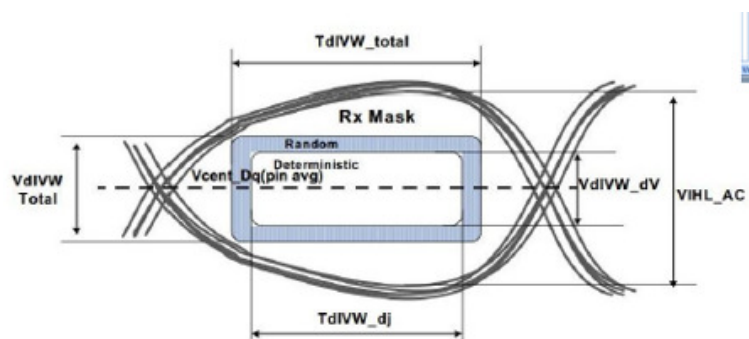
### Relative Propagation Delay Match Groups



# DDR4 compliance

## How an Eye diagram is used

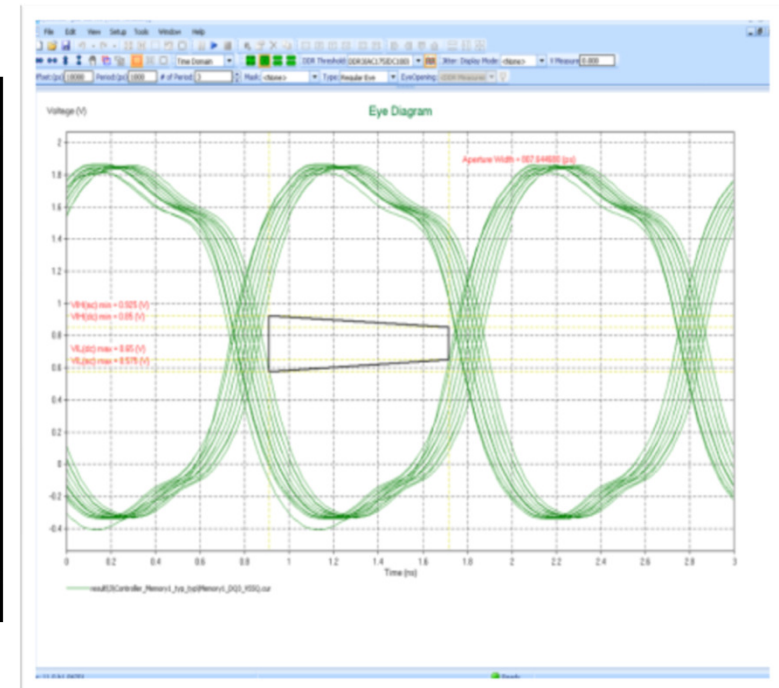
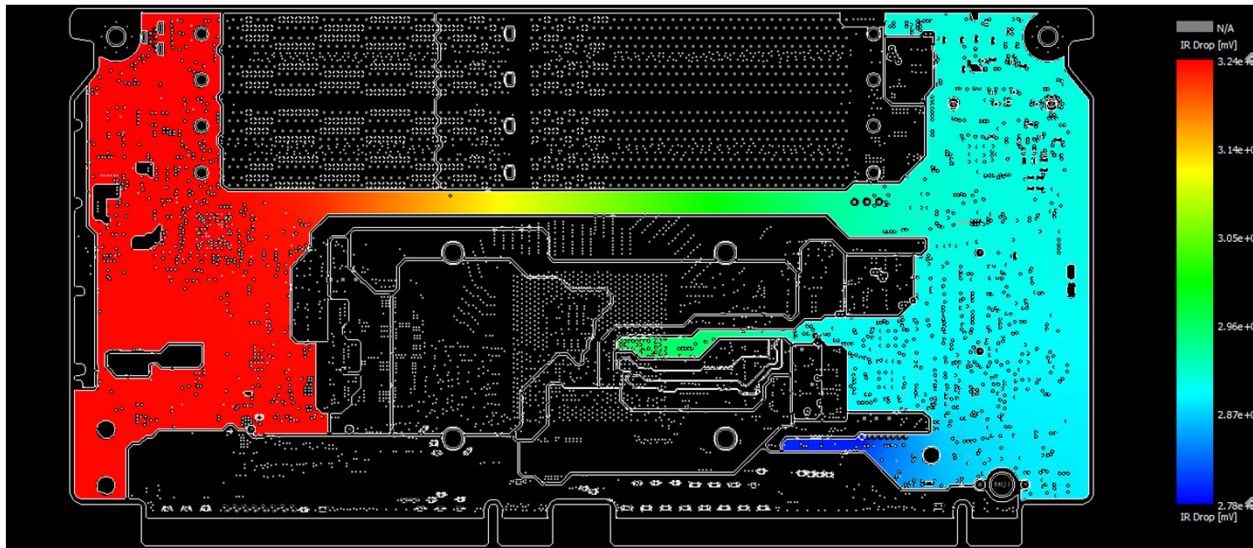
Relative Propagation Delay Match Groups





# How does DC analysis contribute to eye diagrams

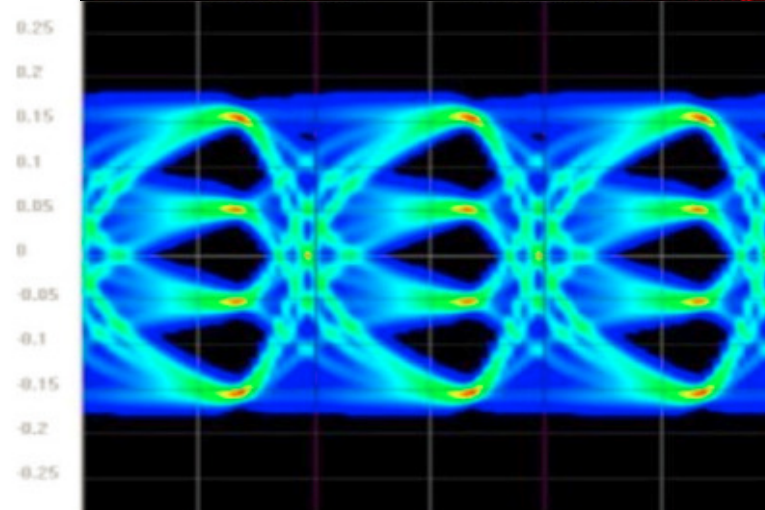
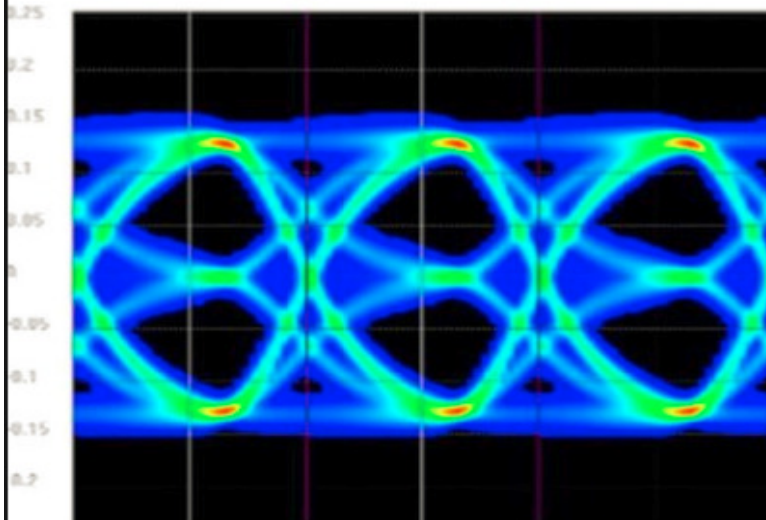
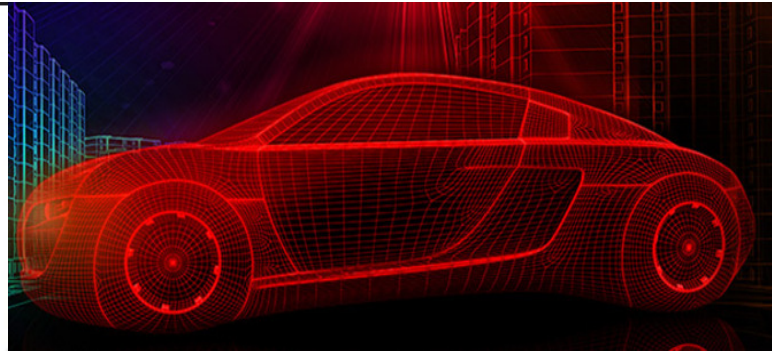
- Proper supply voltage contributes to the height of the eye



# Pulse Amplitude Modulation

## 3 or 4 logic states instead of only 2

- PAM3 and PAM4 signaling and simulation
- PAM-aware example AMI modeling





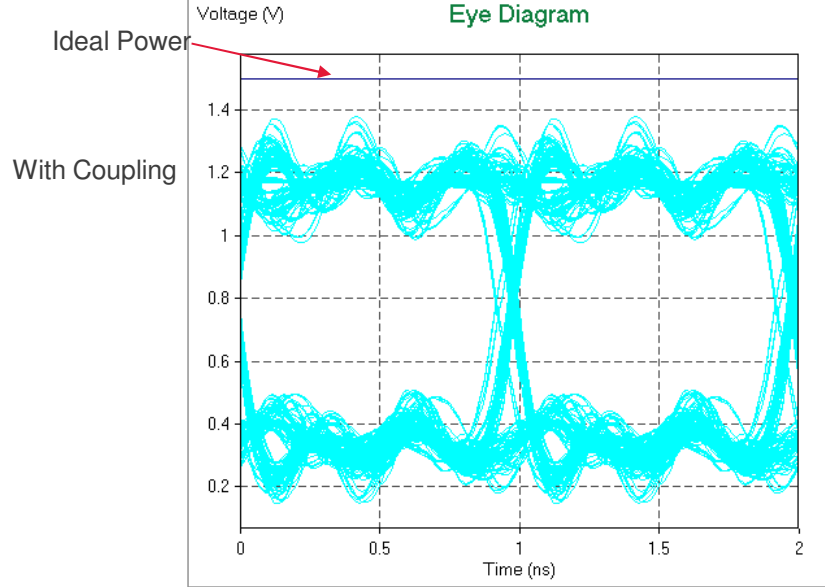
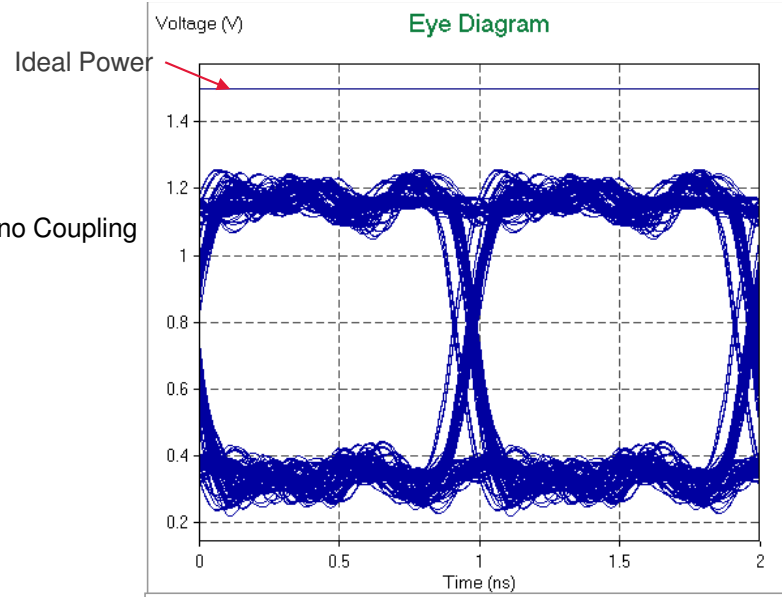
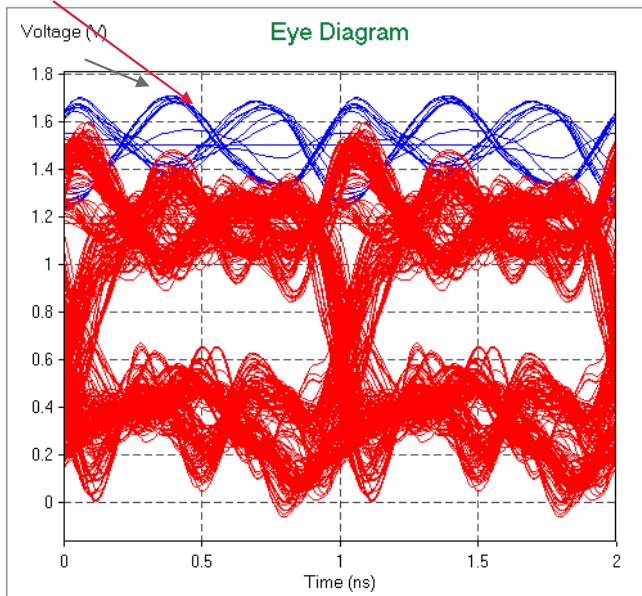
# Loop Inductance “Worthless decoupling capacitors”

# Power Aware

- Power needs to be accounted for as well as the signal
- Coupling with other signals also needs to be accounted for

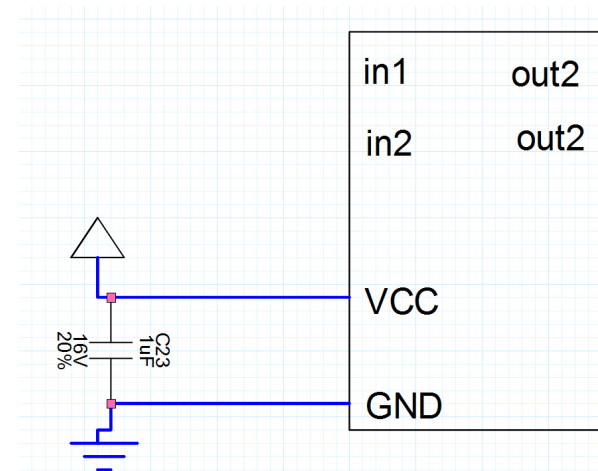
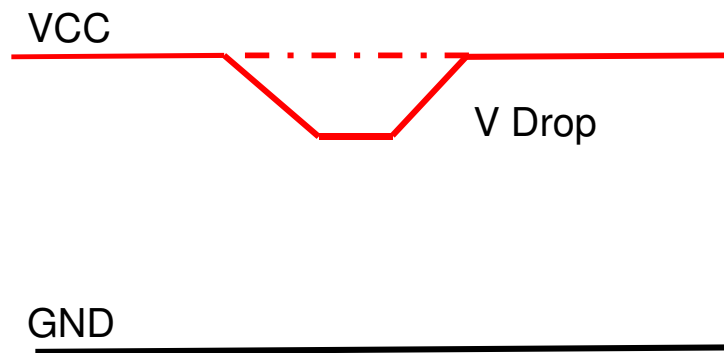
## Power Aware

Real PDN



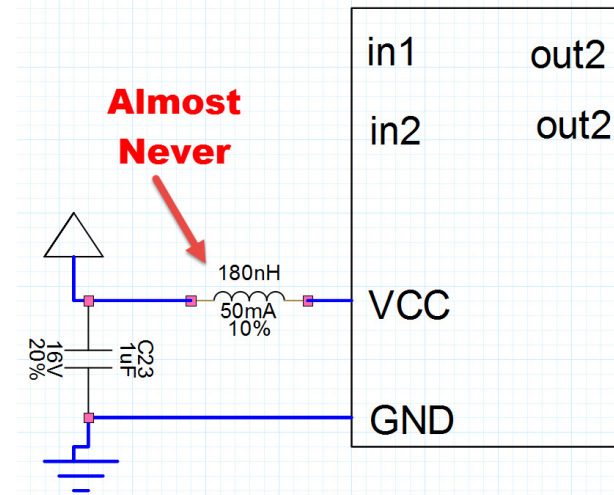
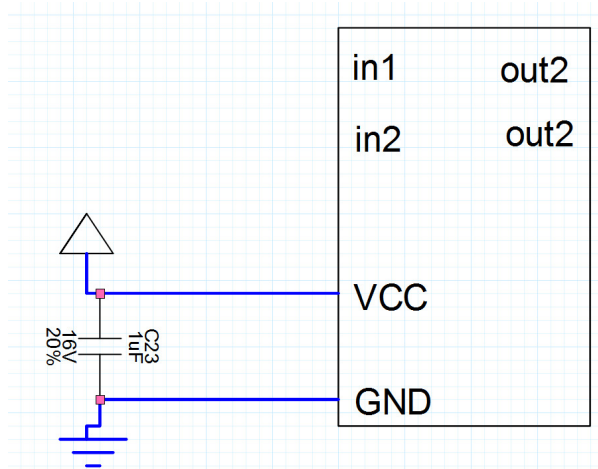
## How a decoupling capacitor maintains ideal power

- A De-Cap reacts to change in voltage by releasing it's charge
- Ideally that charge compensates for the change in voltage, caused by noise or IR drop, seen by the IC



# How a decoupling capacitor becomes useless through loop inductance

- How often does the hardware designer place inductors in series with the decoupling capacitor



- So as a layout designer you have to be careful not to make an inductor out of metal

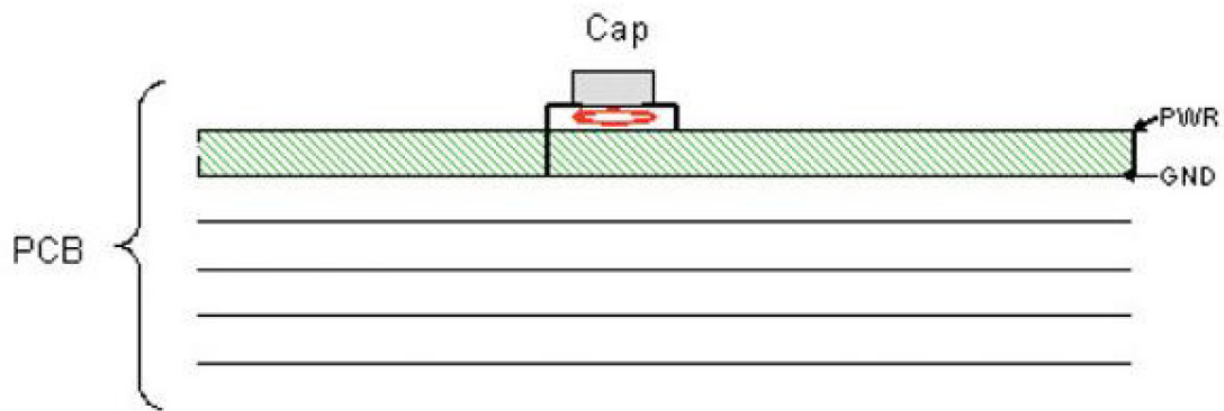


Figure 2. Low inductance connection with capacitor mounted on top of board.

Do this

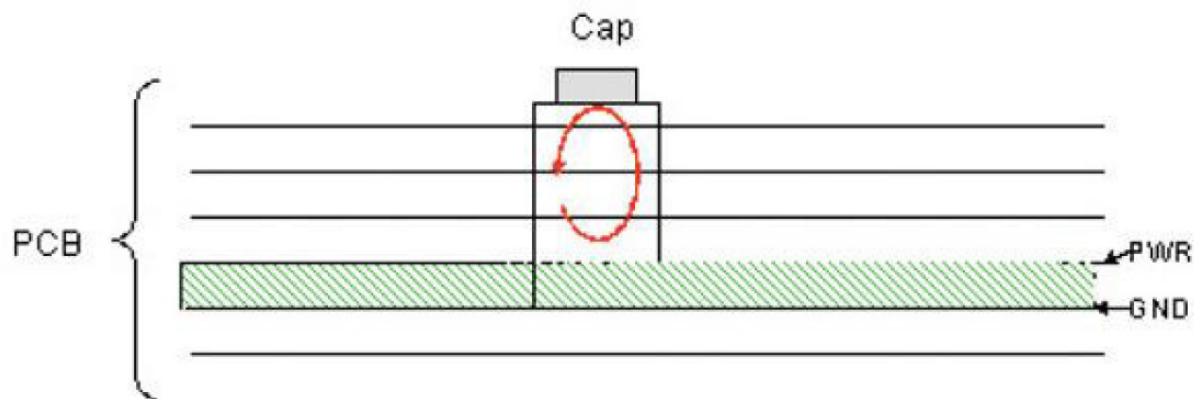
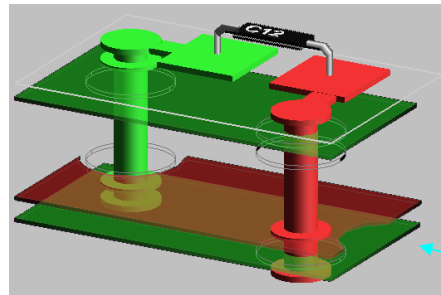


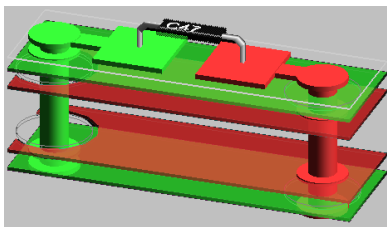
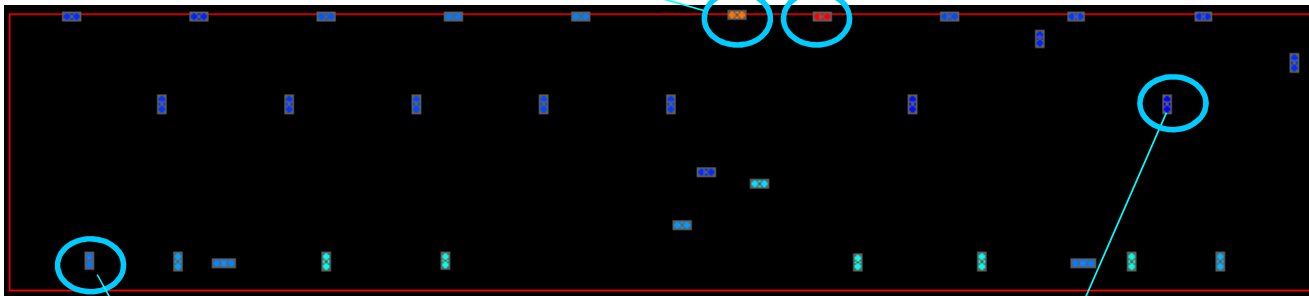
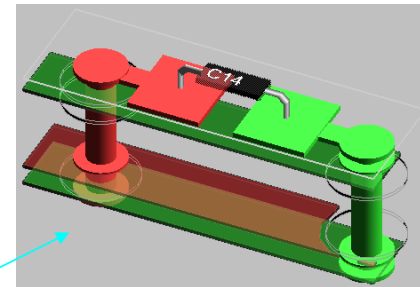
Figure 3. High inductance connection with capacitor mounted on top of board.

Don't do this

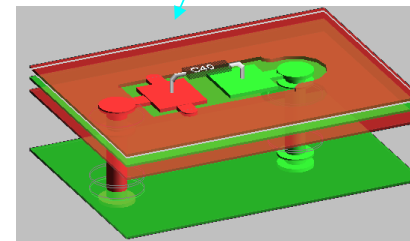
# Loop Inductance



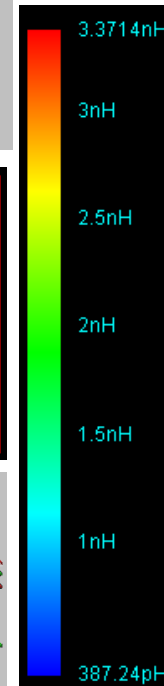
High Loop Inductance



Low Loop Inductance



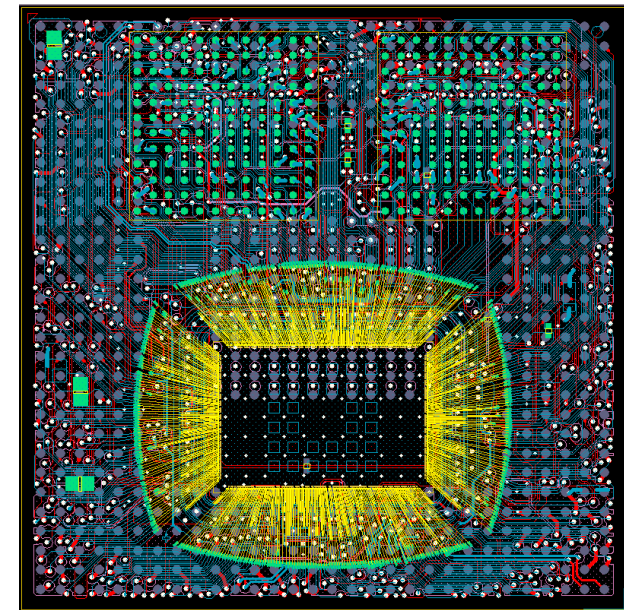
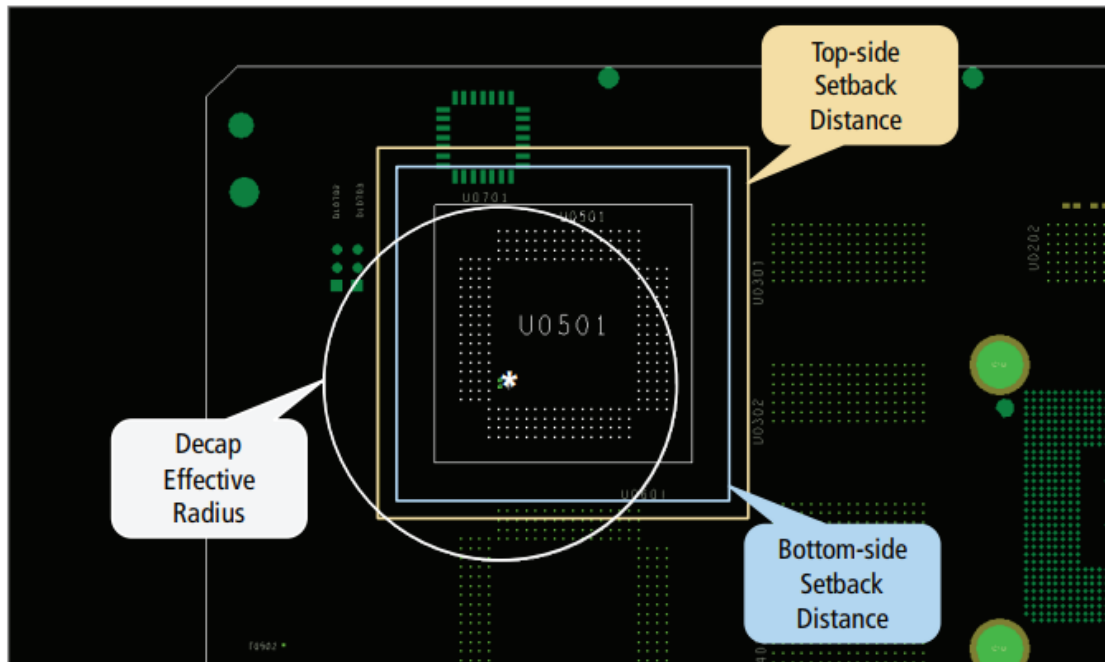
Low Loop Inductance





Smaller capacitors, effective at higher frequency, need to be placed closer to the device to be effective.

De-Caps are often placed inside the IC package design





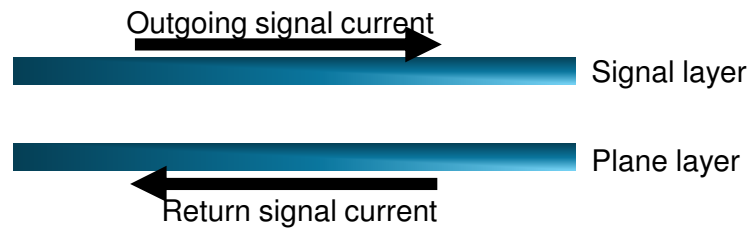
# Return Path Vias

John Carney  
Cadence AE

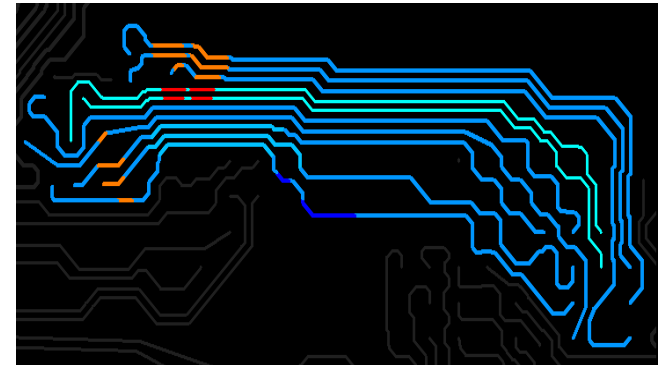
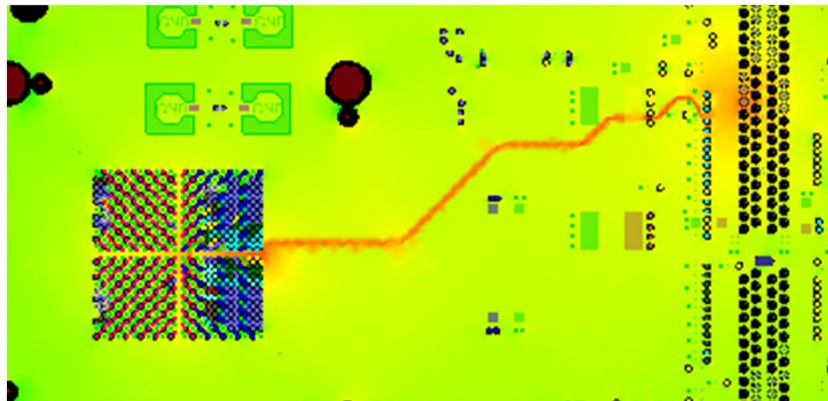
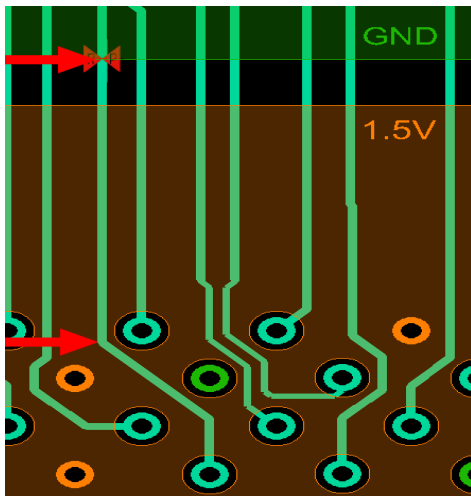
**cādence**<sup>®</sup>

# Understanding Return Path

- Currents must always return to their source.
- Return current will return to their source along the path of the least impedance.



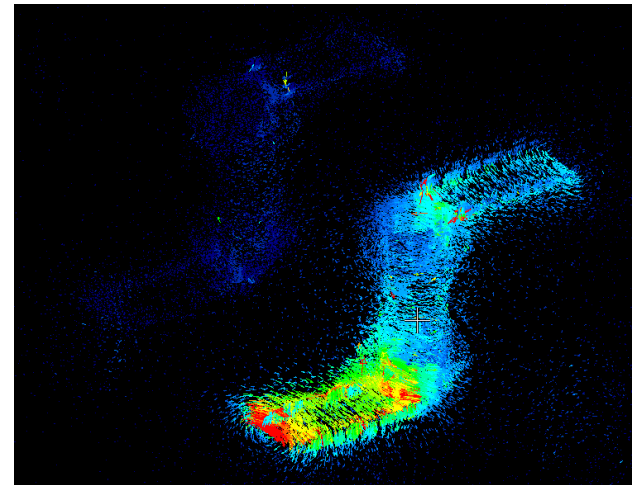
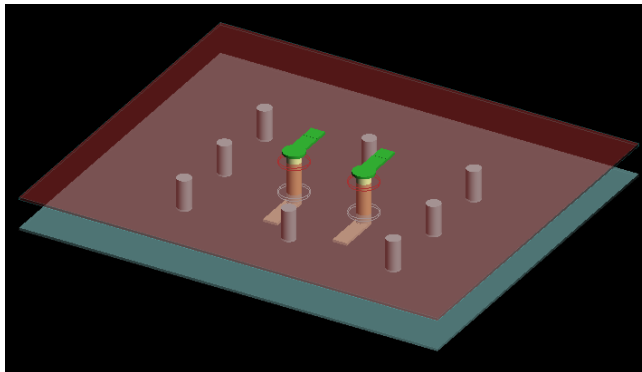
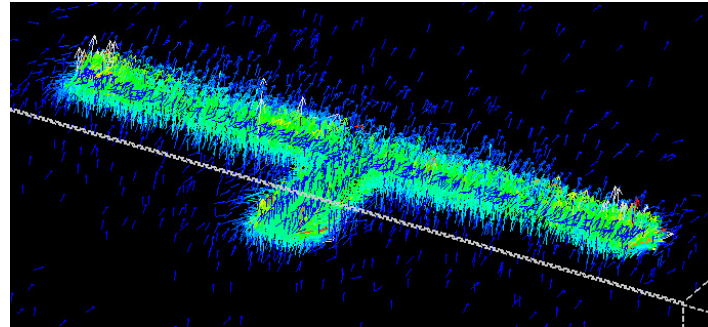
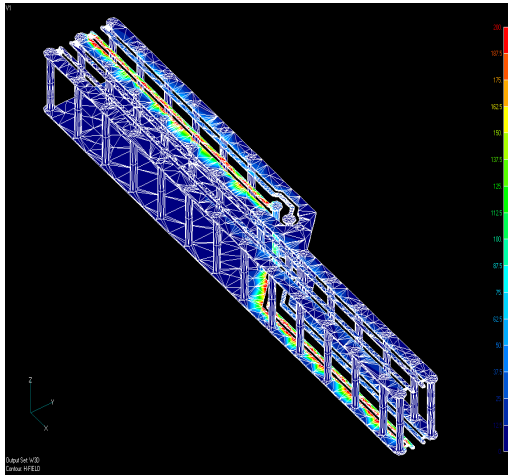
The return currents must complete the loop



Void Crossing Incorrect Reference Plane

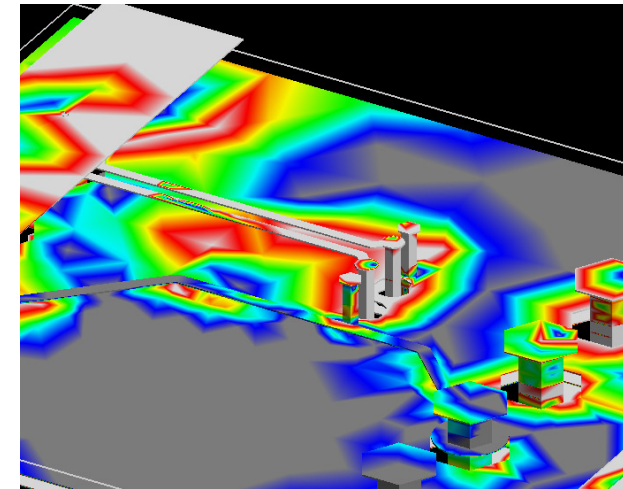
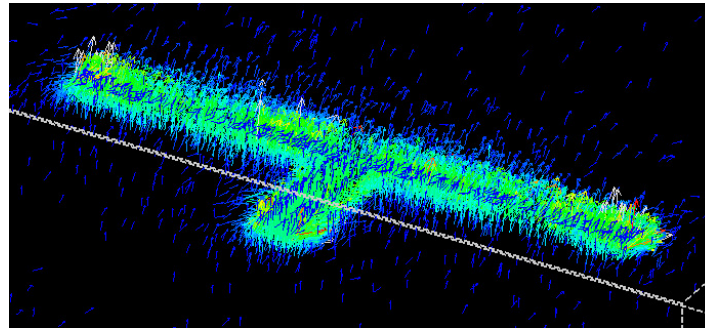
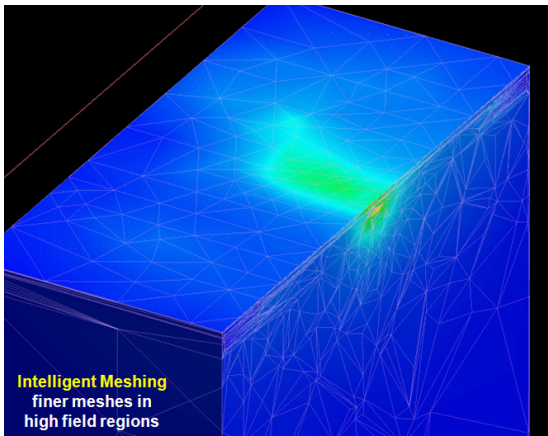
# Electromagnetic fields

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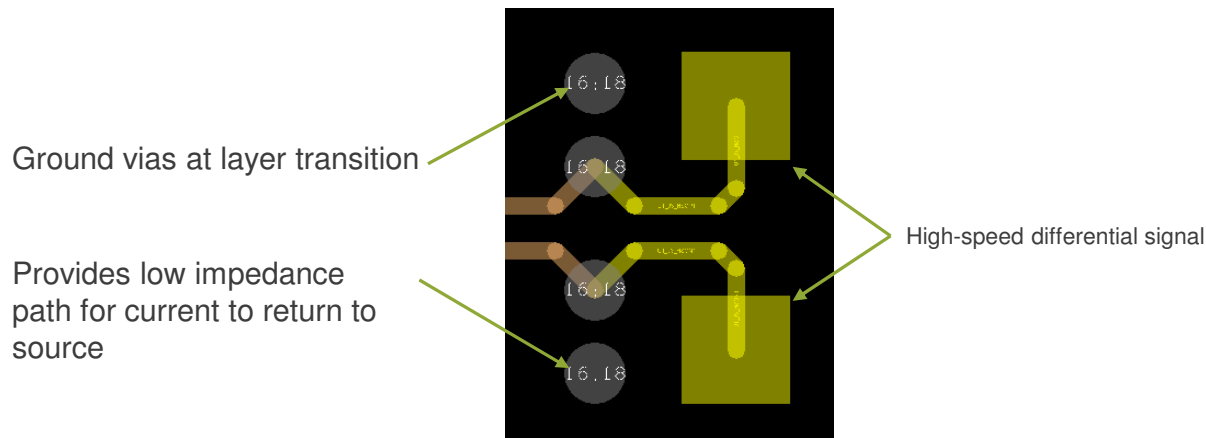
# Electromagnetic fields

- Electric fields on PC boards exist between any two conductors, such as a Microstrip over a return plane.
- Current flows in loops and must have an uninterrupted path back to the source.
- If the return path is broken, the electromagnetic field
  - Will “latch on” to the next closest metal and will not likely be the return path you want.
  - Will “leak” throughout the dielectric and cause common mode currents to flow all over the board, as well as cause cross-coupling of clocks or other high speed signals.



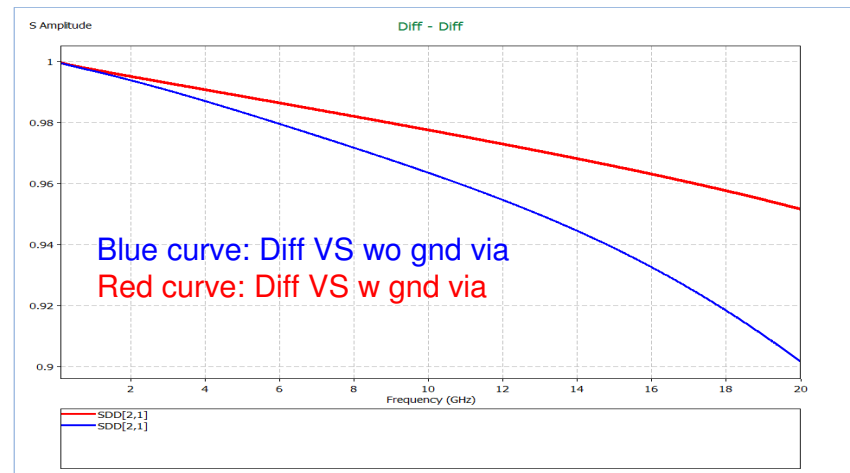
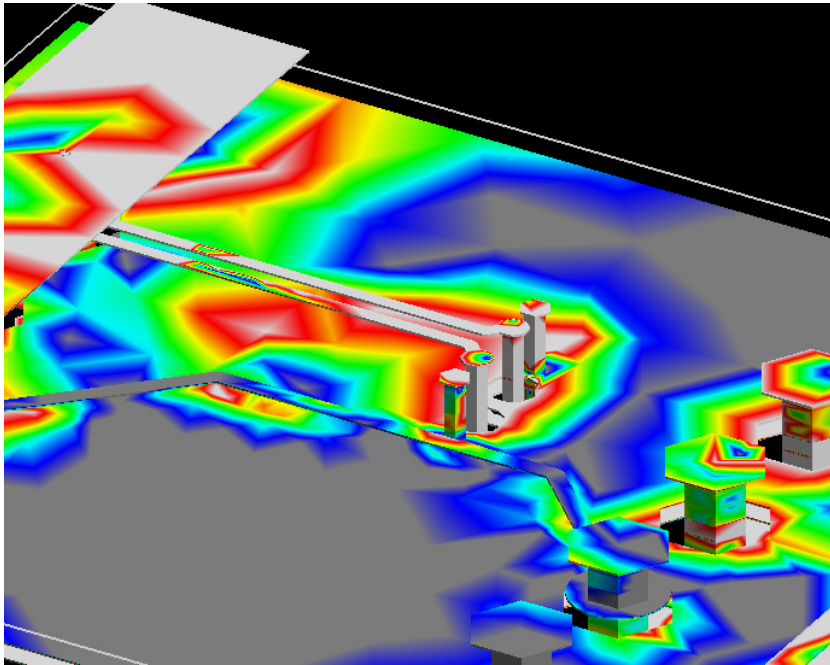
## Providing Return Path

- For system clocks and high speed I/O interfaces such as **DDR**, **PCI Express®**, **USB**, **SATA**, etc. - if via transition is necessary, it is required to place return path via(s) as close as possible to the location of transition
- Without proper placement of return path vias, the return current must find its own way. Results in the current spreading over a large area, which greatly increases the possibility of cross contamination with other signal currents creating a loss of SI



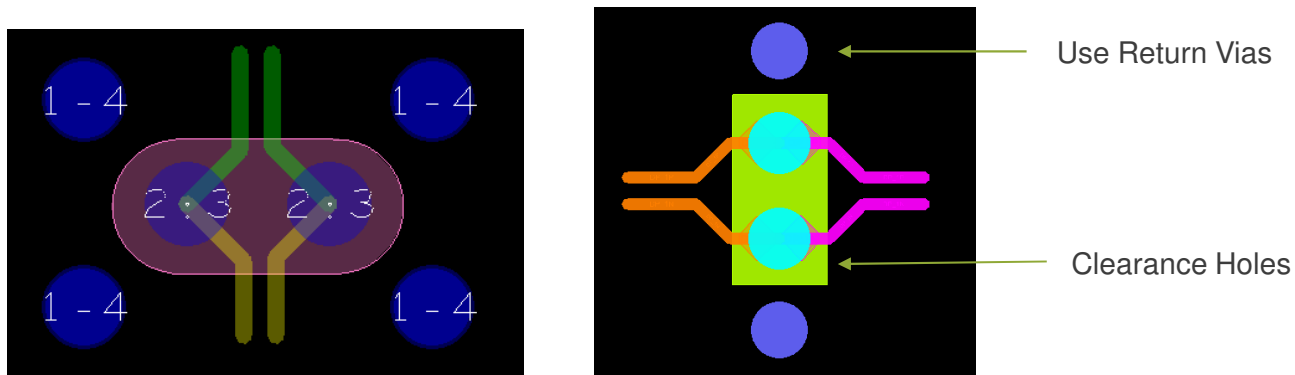
# Return path vias

- Return path vias limit the amount of area the energy can disperse into.
- At multi Ghz these return path vias are typically tuned and driven by simulation.
- Insertion loss (the amount of energy lost in the channel) is also better with return Path vias due to lower impedance



# Most Common Guidelines for High-Speed Via Transitions

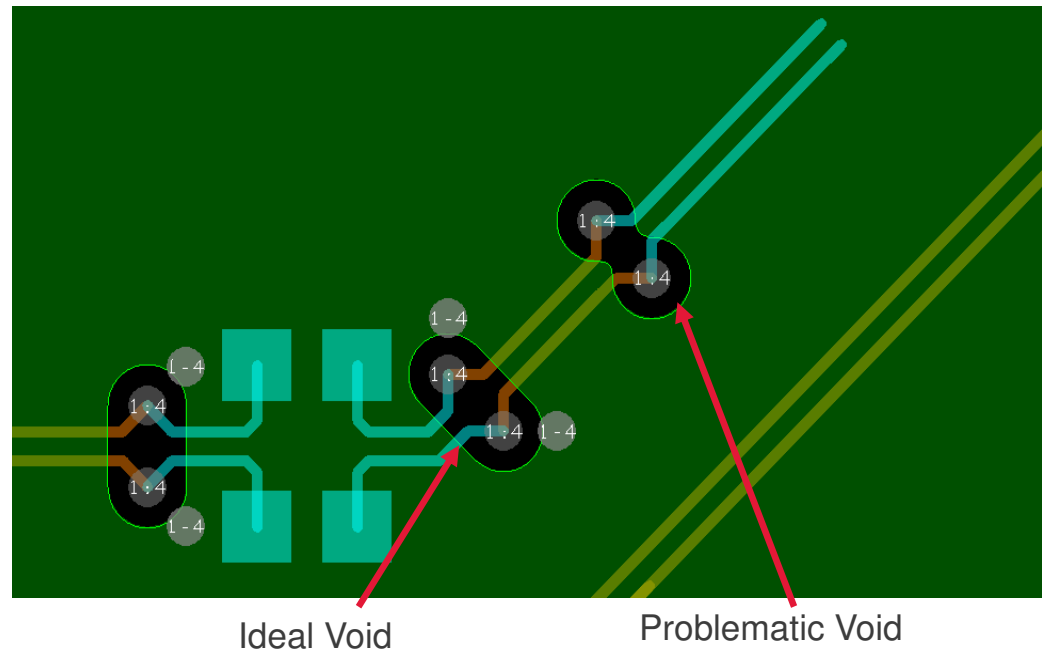
- Use closely coupled impedance matched differential vias
- Use return vias in close proximity to signal vias
- Use large clearance hole (anti-pad) in the via stack



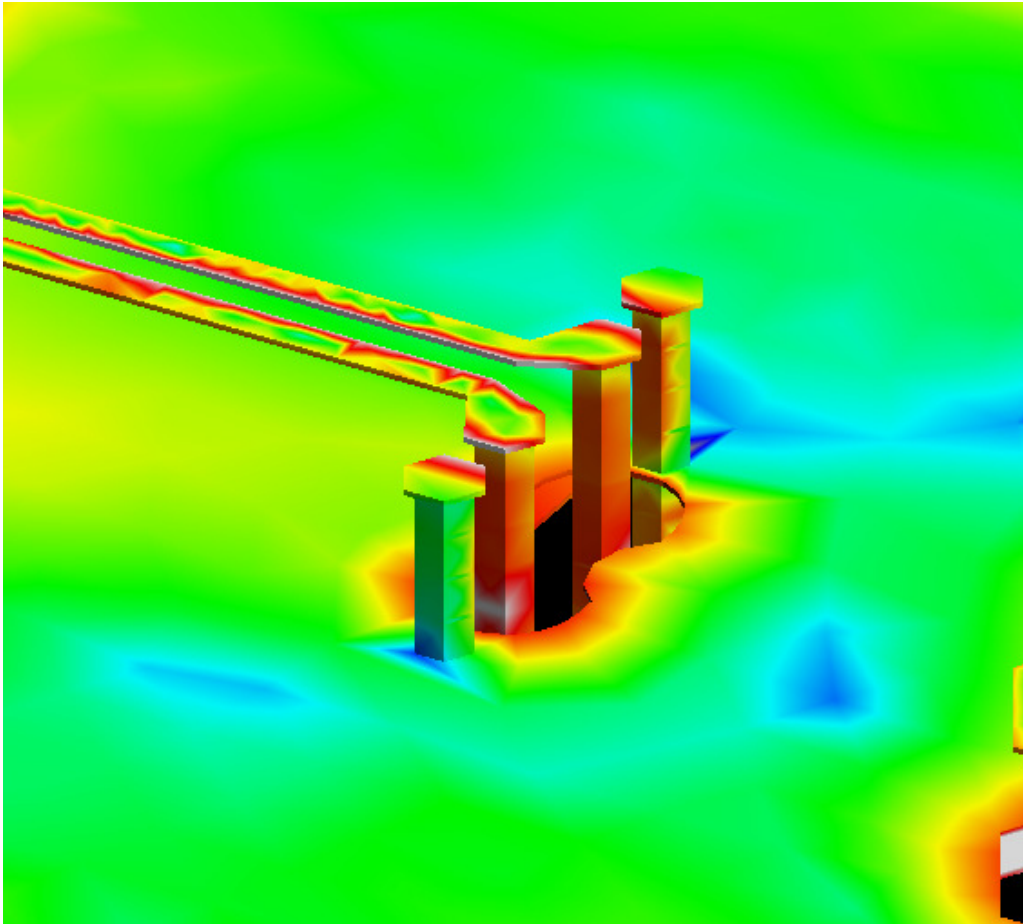


## Diff Pair Via Voiding

- The shape of the void is important
- An oblong instead of a void created by the via/shape clearance is highly preferable at high speeds



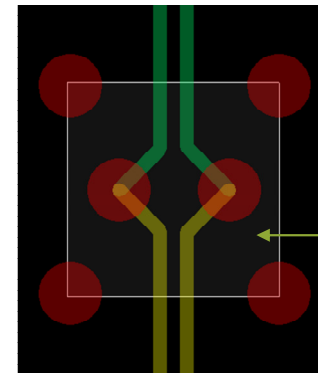
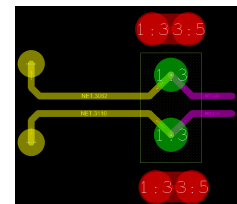
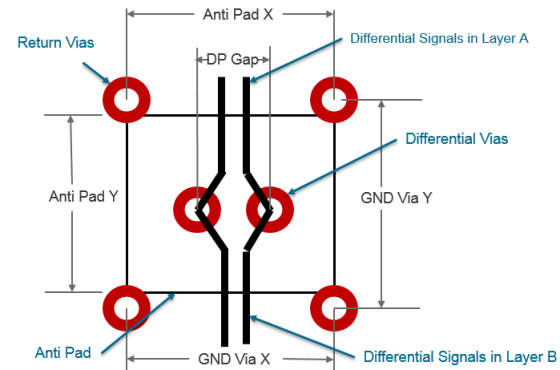
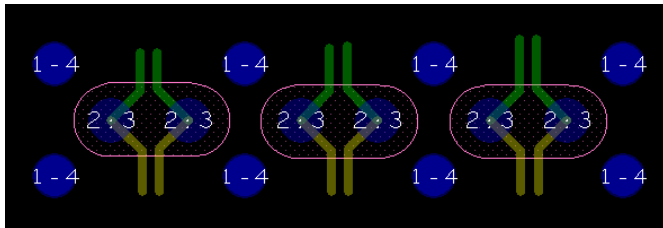
## Differential Vias with bad void



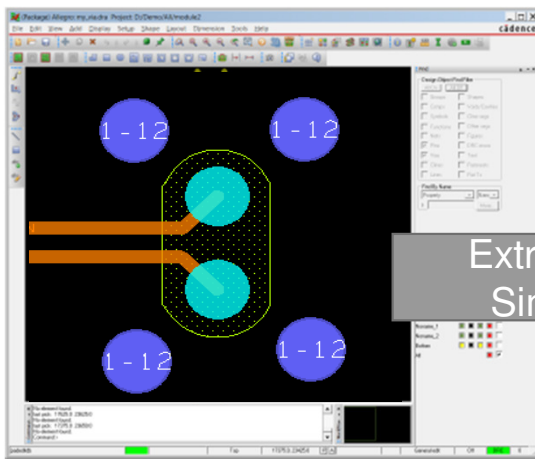
Increased EM coupling to the plane due to the conductor closer to the signal vias

# High Speed Via Structures

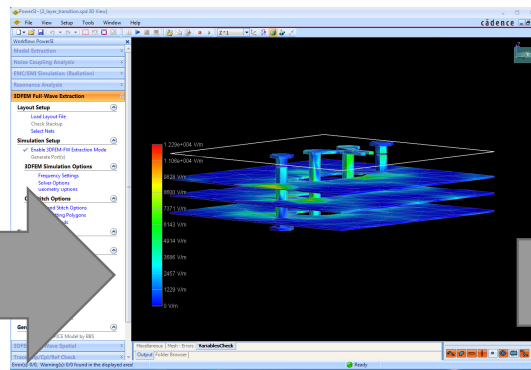
- SI engineers are getting more creative, which results in more complex requirements on:
  - Return path vias: type (thru, BB Stacked/Staggered), quantity, pattern, and proximity locations
  - Differential pair pad entry/exit (trace width, entry/exit pattern)
  - Void (layers, pad clearance, shape)



# Simulation Driven, Optimized, Via Structures

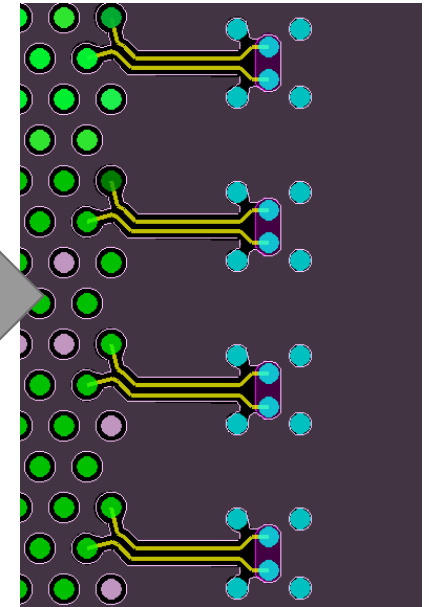


Extract and Simulate



Parametric 3D EM Simulations

Via Structures

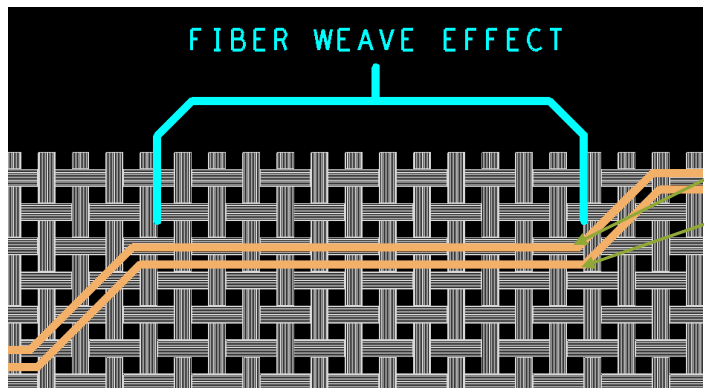




# Fiber Weave

# What is “Fiber Weave Effect”?

- When timing or phase skew caused by fiberglass reinforced dielectric substrate between two transmission lines of the same length happens
- Traces routed directly over the fiberglass weave will see a different Dielectric Constant than the traces that are routed over the voids in the weave where only epoxy resin is present.
- At high data rates, this dielectric constant mismatch can cause signal integrity issues when running these high speed signals parallel to the void areas of PCB fiberglass weave.



Trace running directly over glass fiber

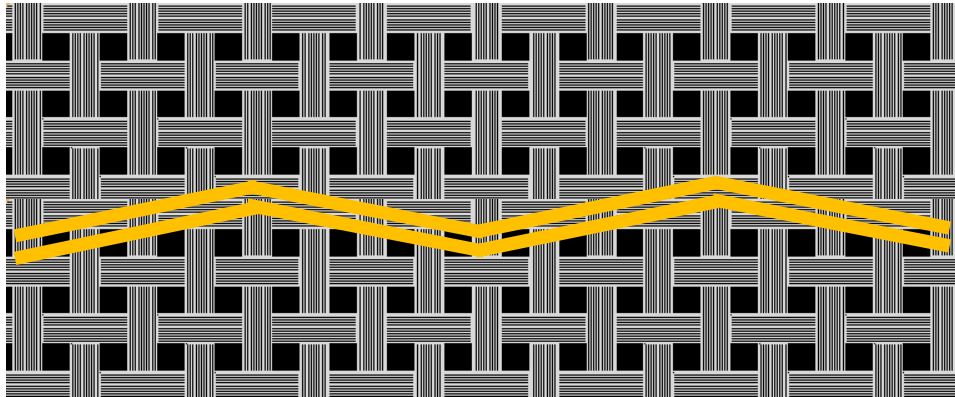
Trace running directly over epoxy

This results in a degraded differential signal as glass and epoxy have different permittivity's on PCBs.

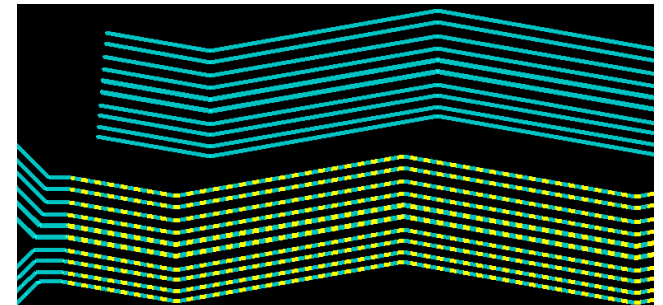
# Typical Layout Routing Guideline

When routing for a considerable length, it is oftentimes recommended to do zigzag routing to mitigate the negative effects of fiber weave on high-speed differential signals by forcing the traces to be out of alignment with the fiber weave.

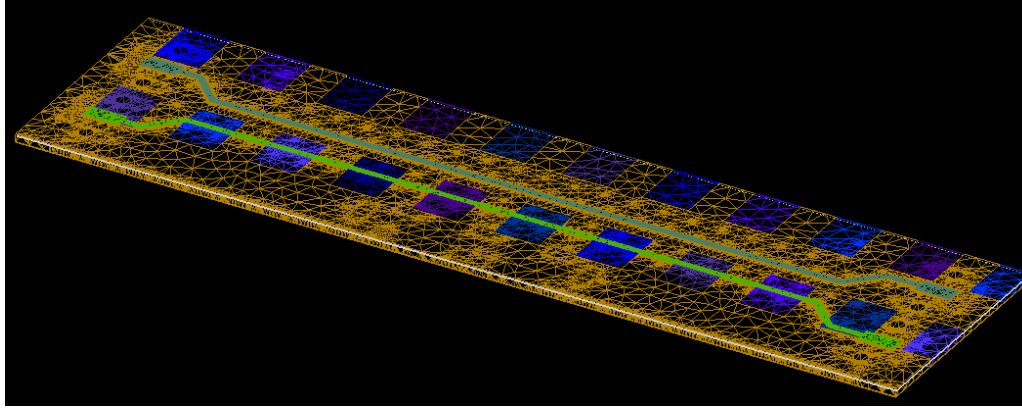
- Angle of zigzag can be 1-10 degrees to skew traces relative to weave. Typical value used is 10 degrees to sufficiently skew trace.



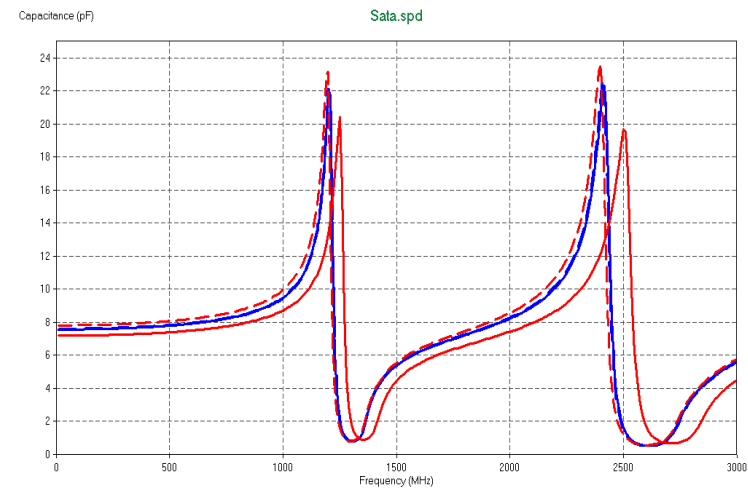
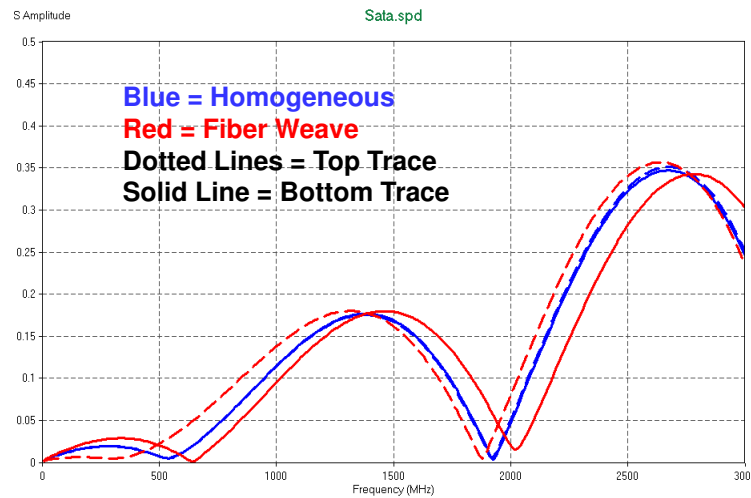
Typical for **>5 GT/s**, the fiber weave effect becomes significant when the trace alignment to weave is 4" or longer.



# Fiber Weave Effects (sample case 1)

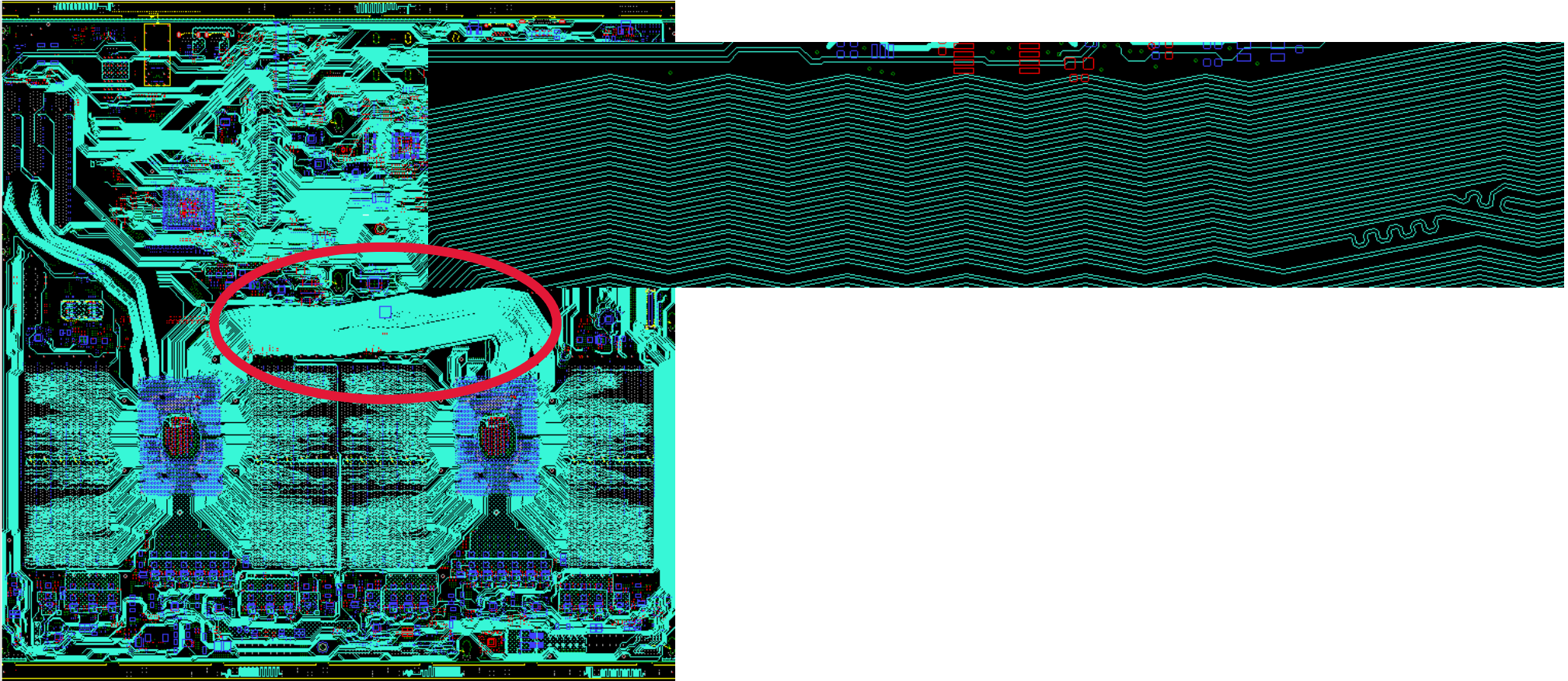


Top trace and bottom trace have different Amplitude(S), Capacitance(c), and Zc due to inhomogeneous materials created by fiber weave.





# Fiber weave compensation example



# 3D Modeling of Fiber Weave Effect

## Test Cases: Channel Simulation Results (3)

### Homogeneous

Characterization Data	= E:\Cadence\Products\PowerSI-
Delay	= 0.48856 ns
Intra-Pair Skew	= 0.38521 ps
Algorithmic Models:	
Rx Models	= C:\Cadence\Sigrity2015\share
Primary Tx Tx1 Models	= C:\Cadence\Sigrity2015\share
Jitter Inputs:	
Random Jitter	= 1 %
Noise Inputs:	
Random Noise	= 1 mV
Eye Contour Measurements:	
Eye Height	= 552 mV
Eye Jitter	= 0.40 UI
Eye Norm Jitter and Noise (NJN)	= 0.81
BER Measurements:	

### With Fiber Weave

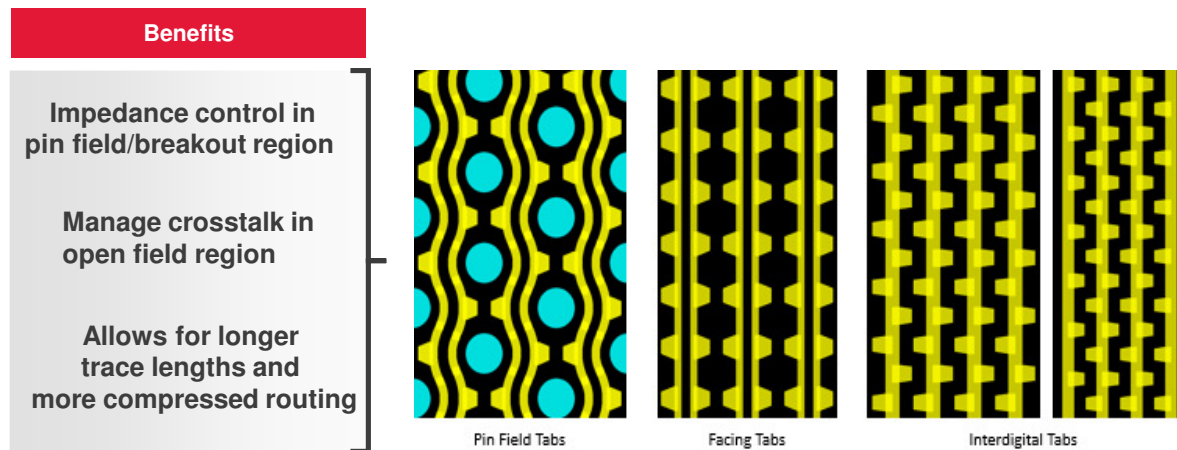
Characterization Data	= E:\Cadence\Products\PowerSI-
Delay	= 0.482429 ns
Intra-Pair Skew	= 14.0522 ps
Algorithmic Models:	
Rx Models	= C:\Cadence\Sigrity2015\share
Primary Tx Tx1 Models	= C:\Cadence\Sigrity2015\share
Jitter Inputs:	
Random Jitter	= 1 %
Noise Inputs:	
Random Noise	= 1 mV
Eye Contour Measurements:	
Eye Height	= 564 mV
Eye Jitter	= 0.34 UI
Eye Norm Jitter and Noise (NJN)	= 0.78
BER Measurements:	



# Tabbed Routing

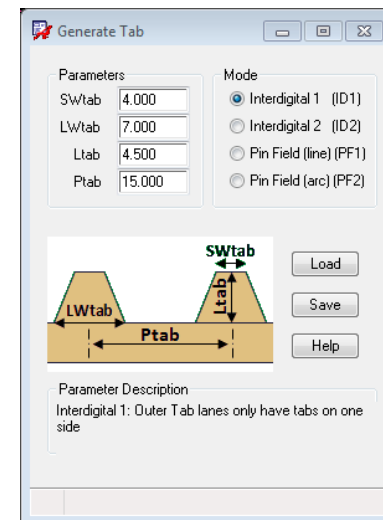
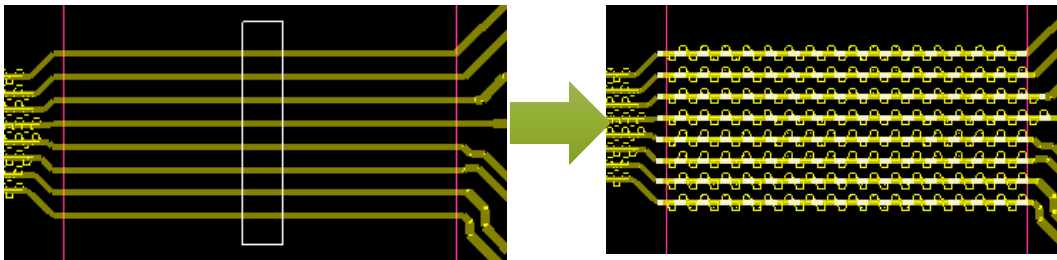
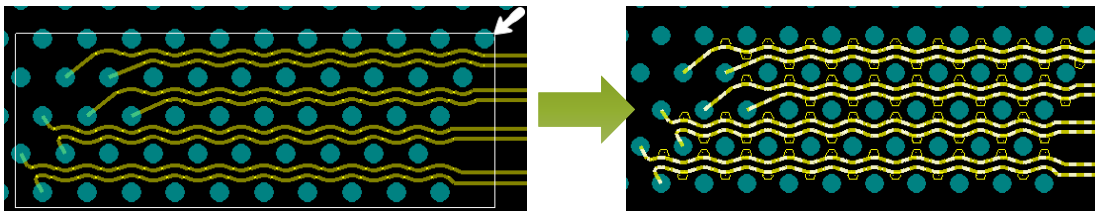
# What is “Tabbed Routing”?

- New routing method in which trapezoidal shapes called tabs are added to parallel traces



# Layout Tips and Techniques

- Tab applications and parameters are typically provided by the IC vendor.



# Tabbed Routing Simulations

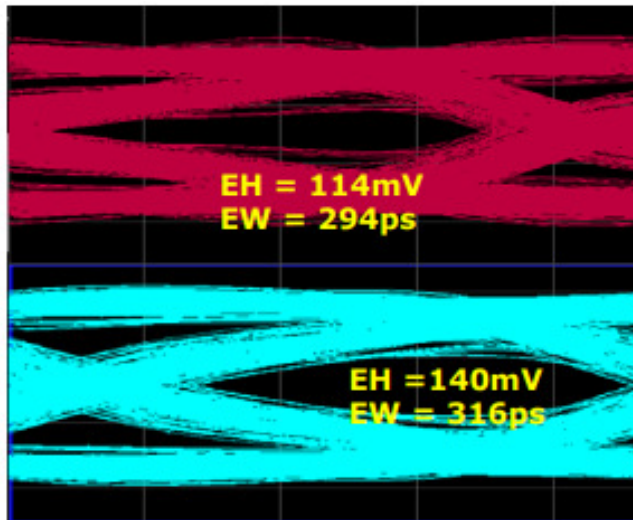


Figure 9: Eye diagram comparison. Red: normal microstrip wiring. Blue: tabbed line wiring.

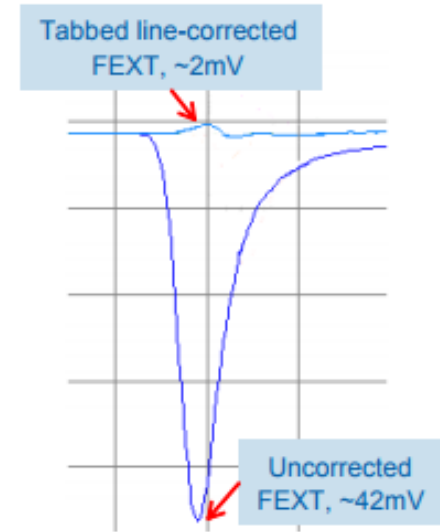
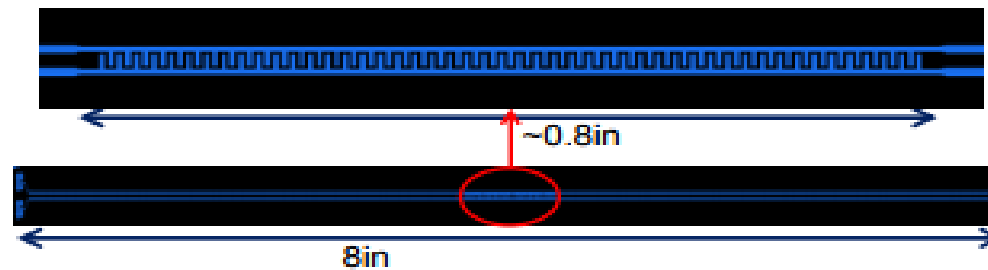
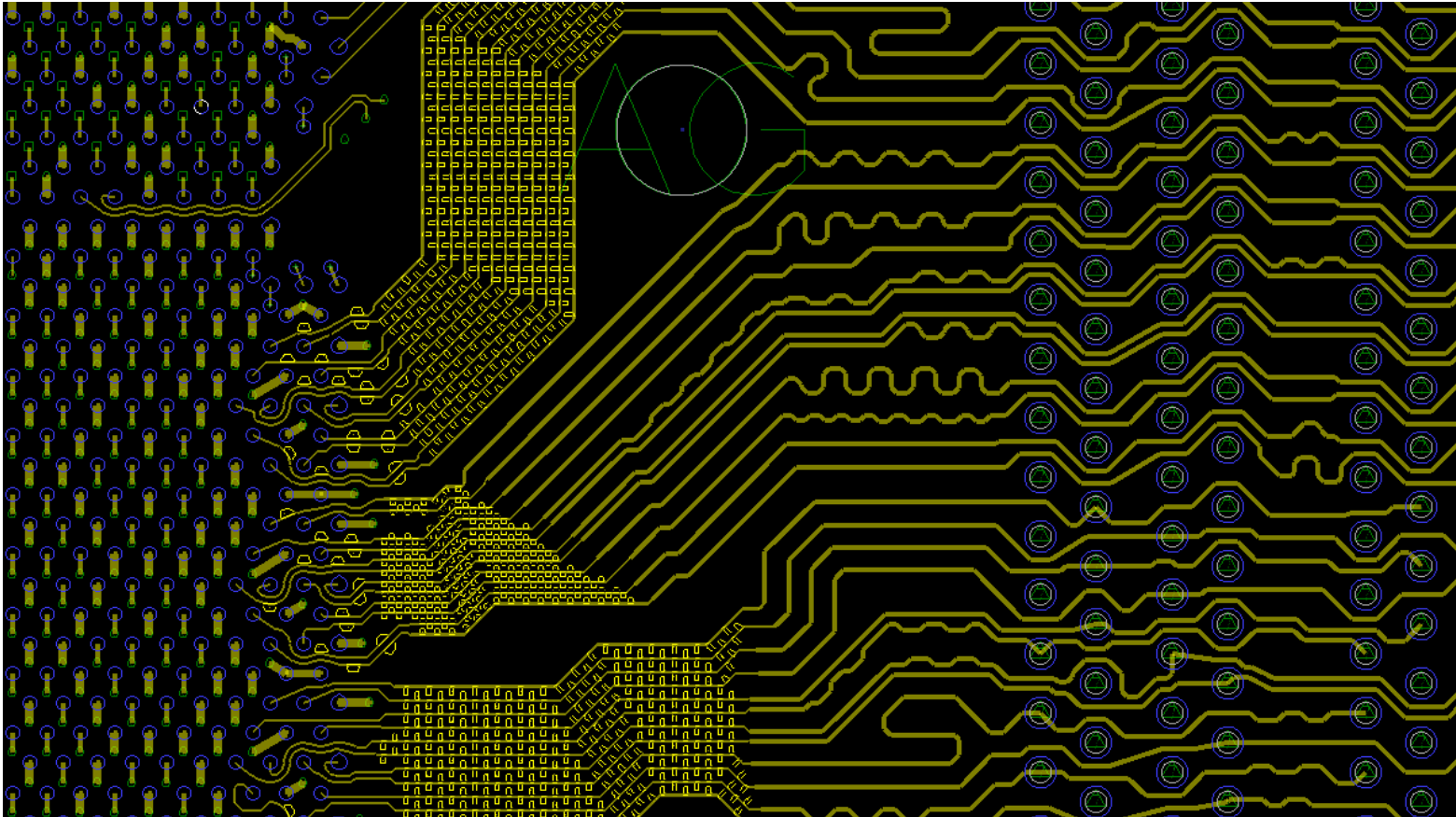


Figure 3: Measurement results showing net FEXT amplitude reduction due to Type (II) tabbed line compensation

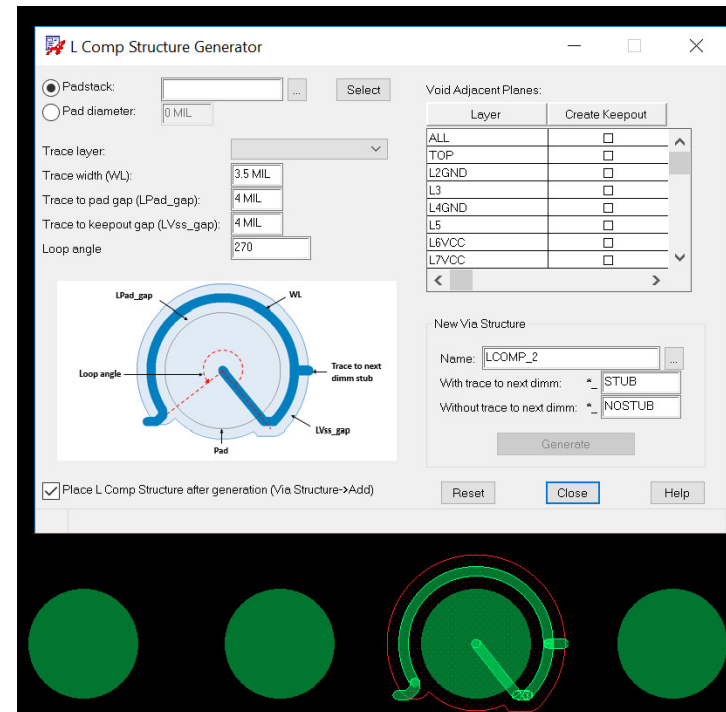


# Tabbed Routing Example



# Inductance (L) Compensation Structures

- Recent advances in high-speed design have required complex structures for proper performance
- Adding inductive structures helps counter component capacitance





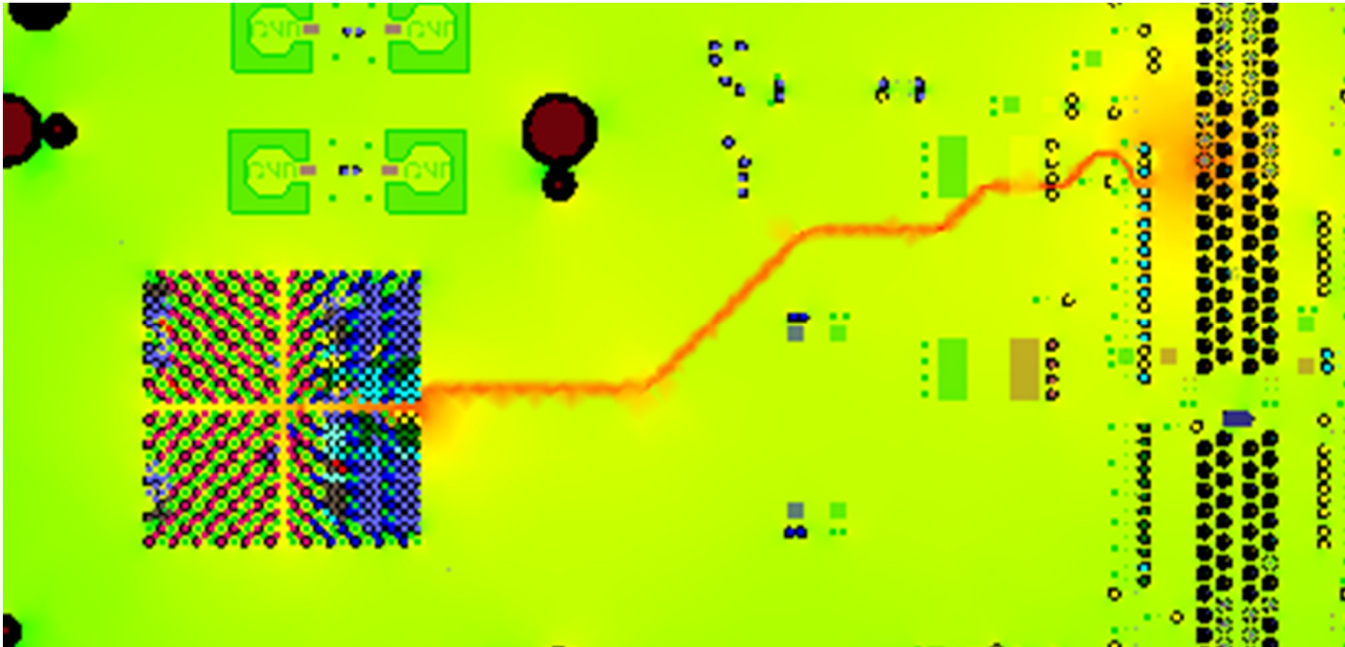


END



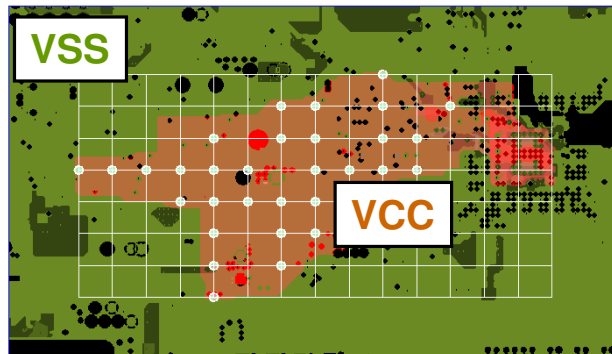
# Extra slides

# Return path analysis

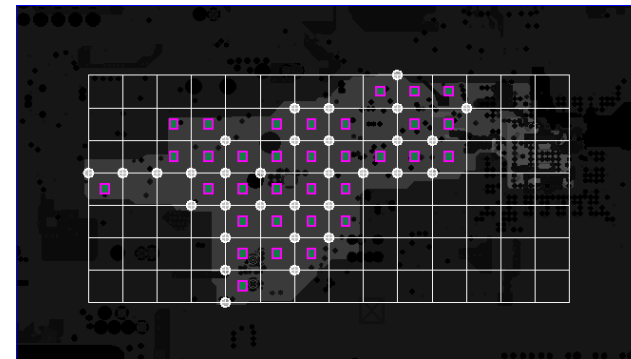


# How to Reduce PDN Emissions

- Reduce impedance throughout the entire PDN
  - reducing device impedance tends to reduce emissions, but is not guaranteed to do so
    - especially for high device decap count
  - reducing PDN impedance assures reduced emissions
  - new capacitors are usually required

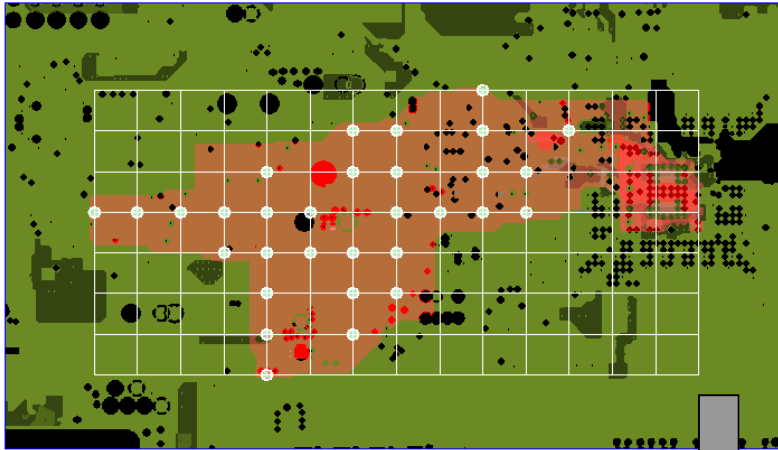


● Impedance observation locations



■ New emicap candidate locations

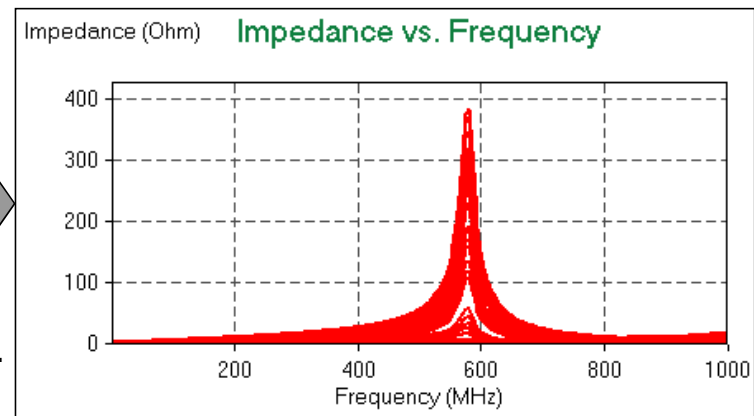
# PDN Impedance Sample Locations



Consider 31 impedances across the power/ground cavity at all X-Y gridline intersections that lie with the cavity boundary.

*NOTE: Not all gridline intersection impedances are used because the point is not within the PDN parallel plate cavity.*

All 31 PDN impedances have a 580MHz peak.



# EMI Optimization Setup

## Objective

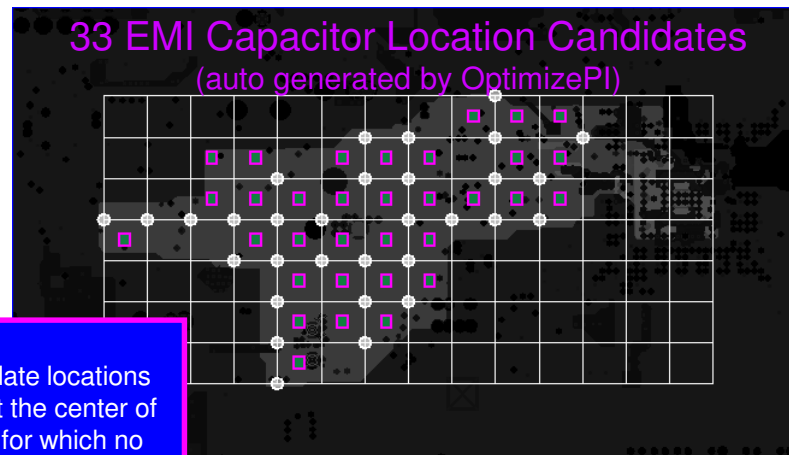
Determine number of capacitors, types, and locations to improve EMI radiation.

① Optimization Objective

Best Performance vs. Number of Capacitors
---

② Optimization Frequency

Starting Frequency	Ending Frequency
10MHz	1GHz



**NOTE:**  
Emicap candidate locations are selected at the center of grid cell areas for which no capacitor now exists.

③ 5 Capacitor Type

Cnom(nF)	Size
10	0402
22	0402
33	0402
47	0402
100	0402

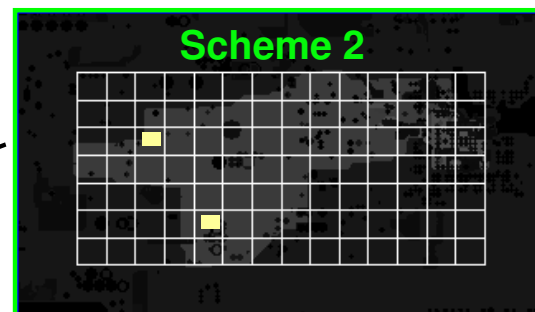
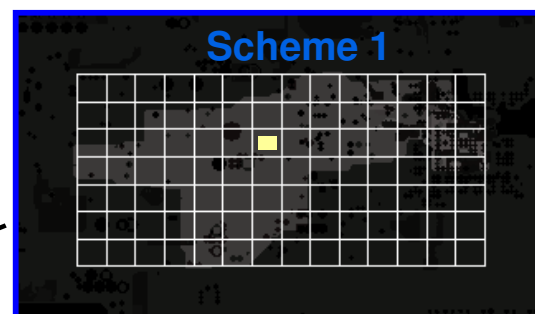
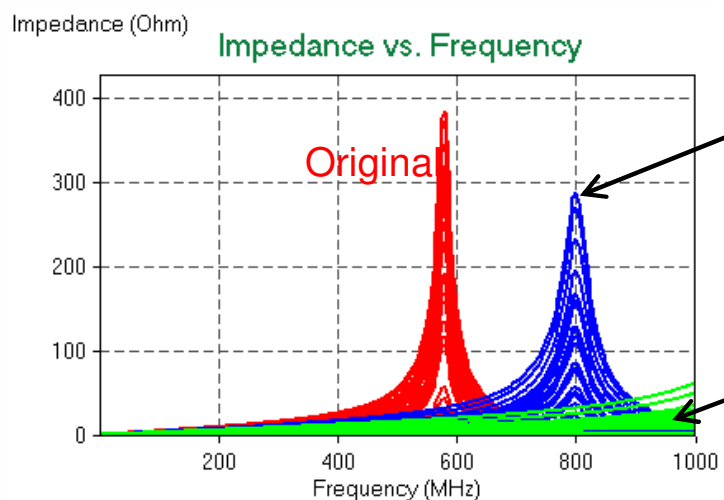
④ Limit Number of Capacitors to 5

Optimization Range	Min	Max
Best Performance vs. Number of Capacitors	1	5

# EMI Optimization Result

## *Impedance at all PDN locations*

Scheme ID	Number
Original Scheme	0
Scheme 1	1
Scheme 2	2
Scheme 3	3
Scheme 4	4
Scheme 5	5



Scheme 2: OptimizePI predicts adding 100nF at these two locations will significantly improve power plane impedance at high frequency.

*We know that reduced PDN impedance implies reduced emissions.*

NOTE: Neither of the capacitors from the optimal 2-emicap scheme is in the same location as the 1-emicap scheme. This contrasts with iterative manual schemes to eliminate resonances.

### L Comp Structure Generator

Padstack:  ...   
 Pad diameter: 0 MIL

Trace layer:   
 Trace width (WL): 3.5 MIL  
 Trace to pad gap (LPad\_gap): 4 MIL  
 Trace to keepout gap (LVss\_gap): 4 MIL  
 Loop angle: 270



Place L Comp Structure after generation (Via Structure->Add)

Void Adjacent Planes:

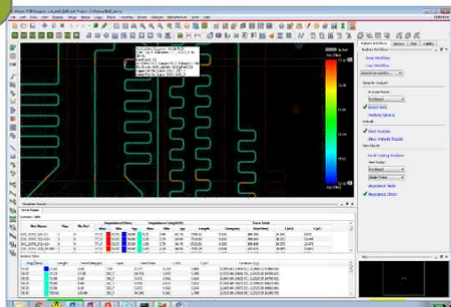
Layer	Create Keepout
ALL	<input type="checkbox"/>
TOP	<input type="checkbox"/>
L2GND	<input type="checkbox"/>
L3	<input type="checkbox"/>
L4GND	<input type="checkbox"/>
L5	<input type="checkbox"/>
L6VCC	<input type="checkbox"/>
L7VCC	<input type="checkbox"/>

New Via Structure  
 Name: LCOMP\_2  
 With trace to next dimm: \*\_STUB  
 Without trace to next dimm: \*\_NOSTUB





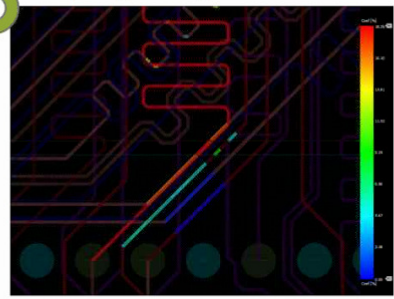
1 Impedance Analysis and Vision



Analysis data on canvas and in tables  
Cross-probe, zoom into problem areas

Quickly identify nets that are out of spec  
Sliders on scale allow for filtering of view

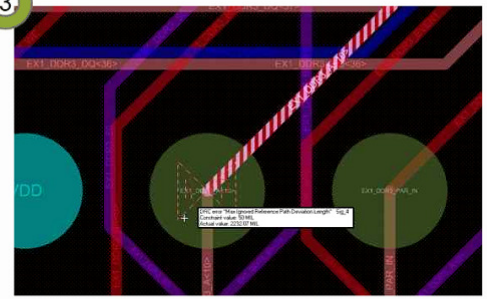
2 Coupling Analysis and Vision



View victim and aggressor  
nets on canvas

Quickly identify nets that are coupled  
Sliders on scale allow for filtering of view

3 Return Path DRC



Signal not next to  
required Ground Plane

Identify critical nets without a  
reference plane quickly  
Above or below or both

# Mutual Inductance

Understanding Inductance in the Real-World | Interference Technology

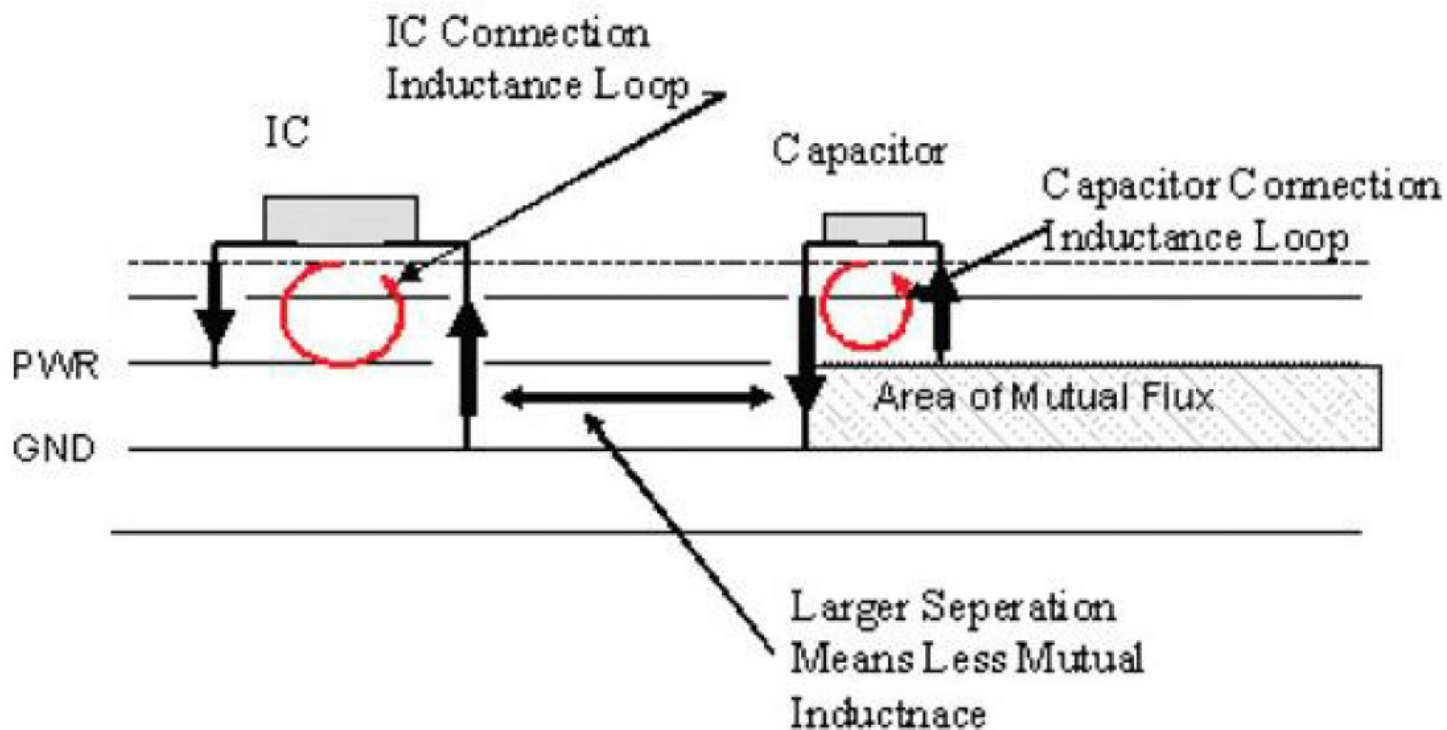
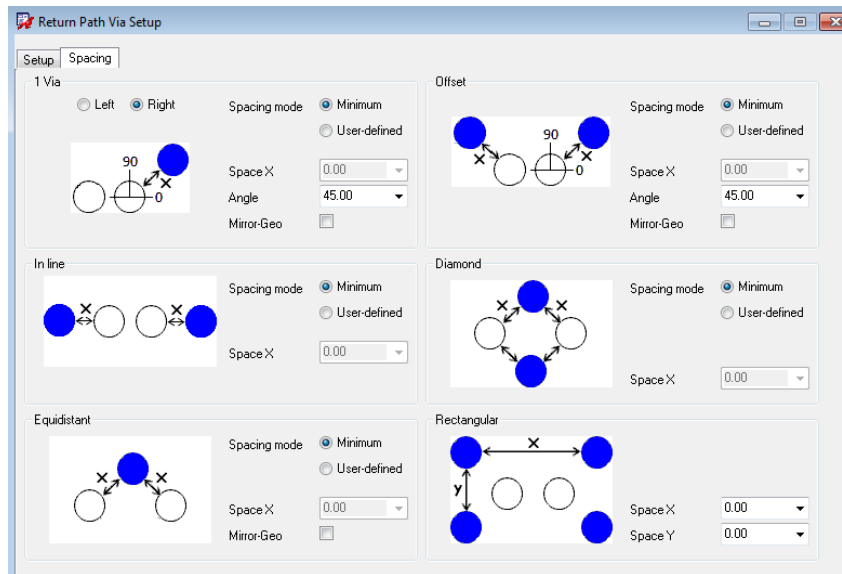


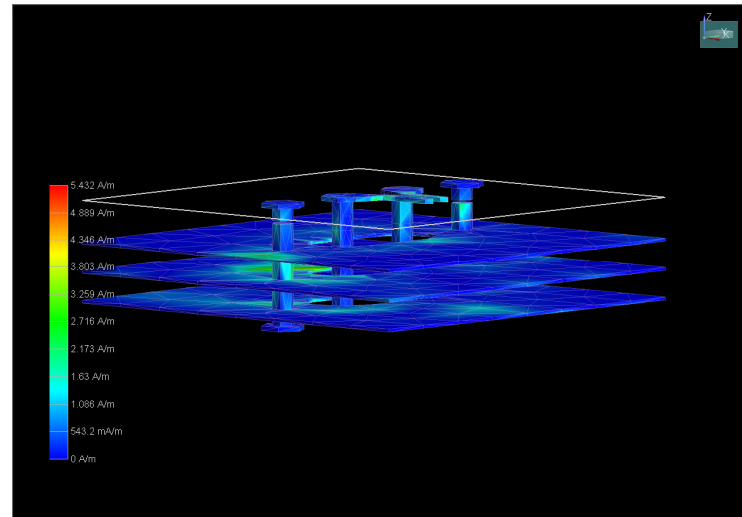
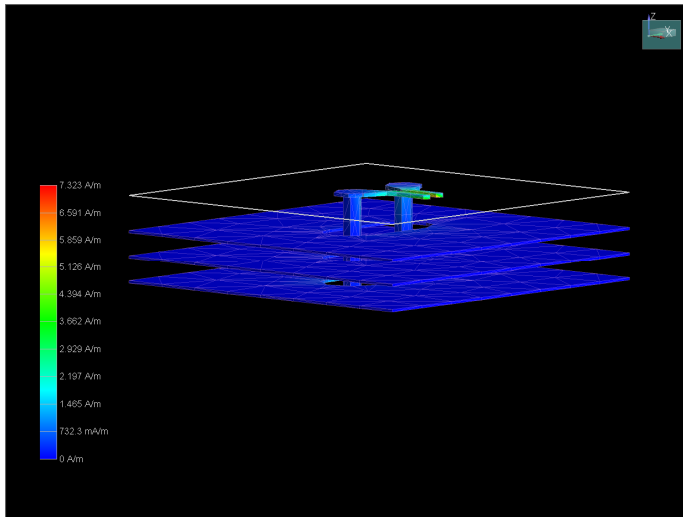
Figure 6. Mutual inductance between decoupling capacitor and IC.

# Return Path Vias

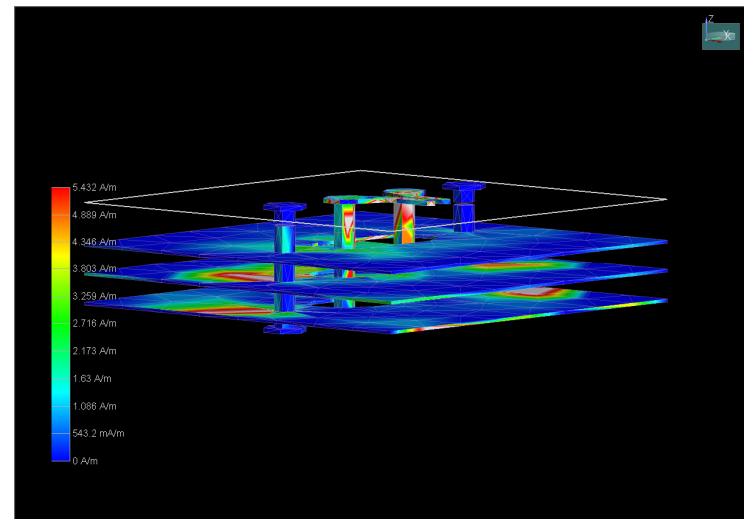
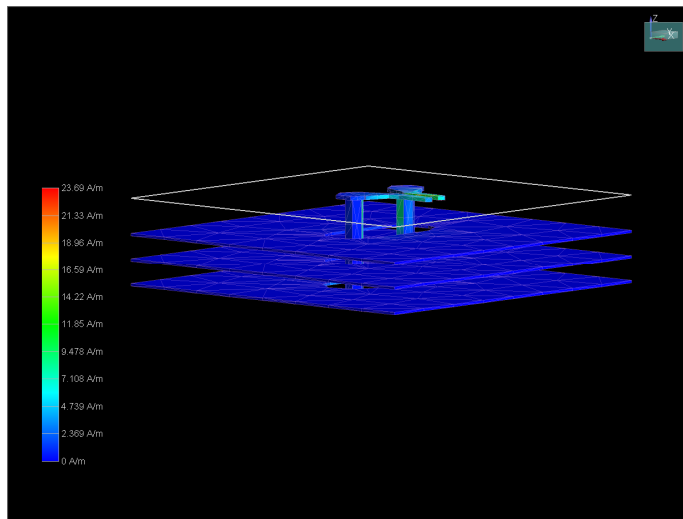


Differential and Single Ended  
Parametric using design guidelines  
Most popular common patterns  
Not simulation driven  
Show video of them being added and moved

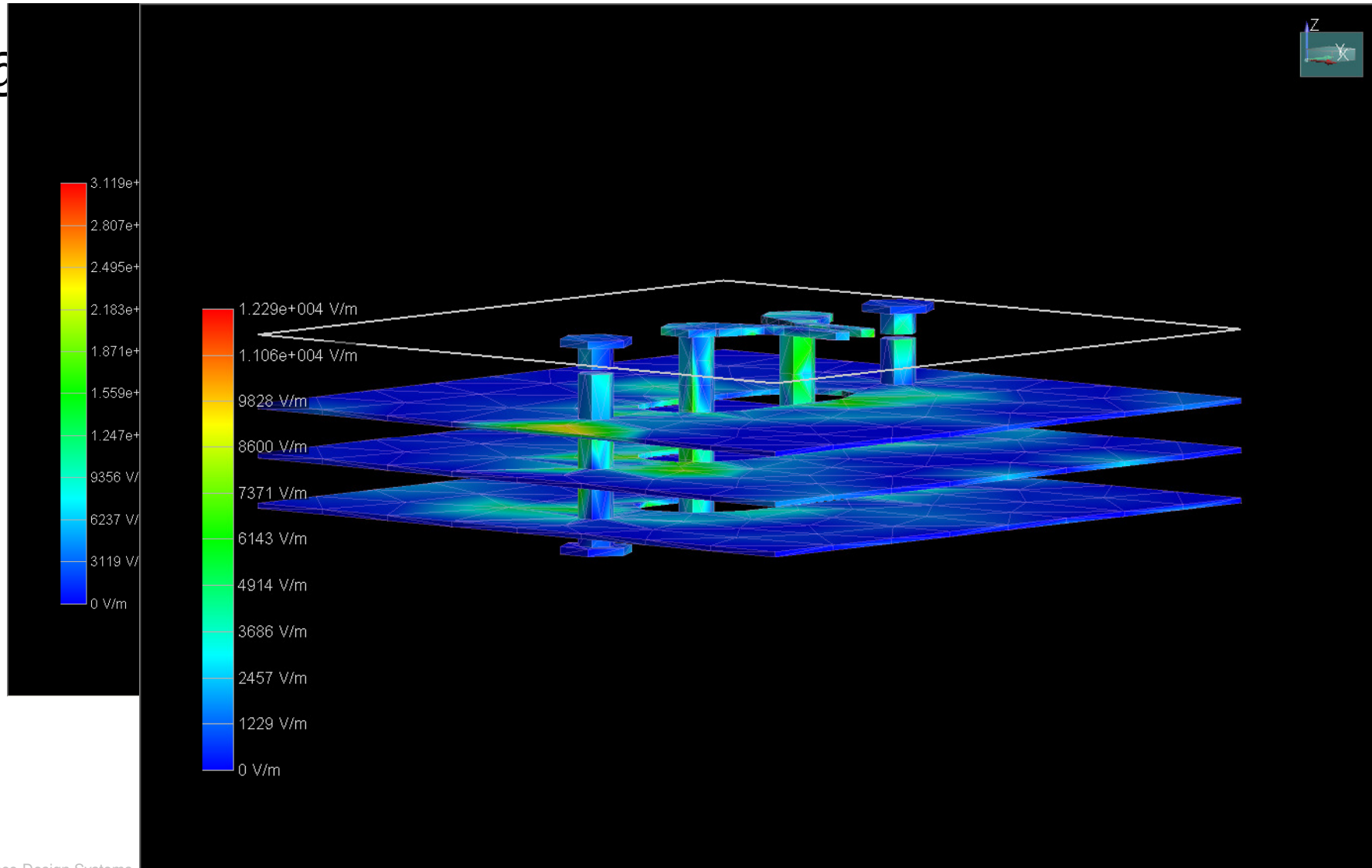
# H Field @1GHz



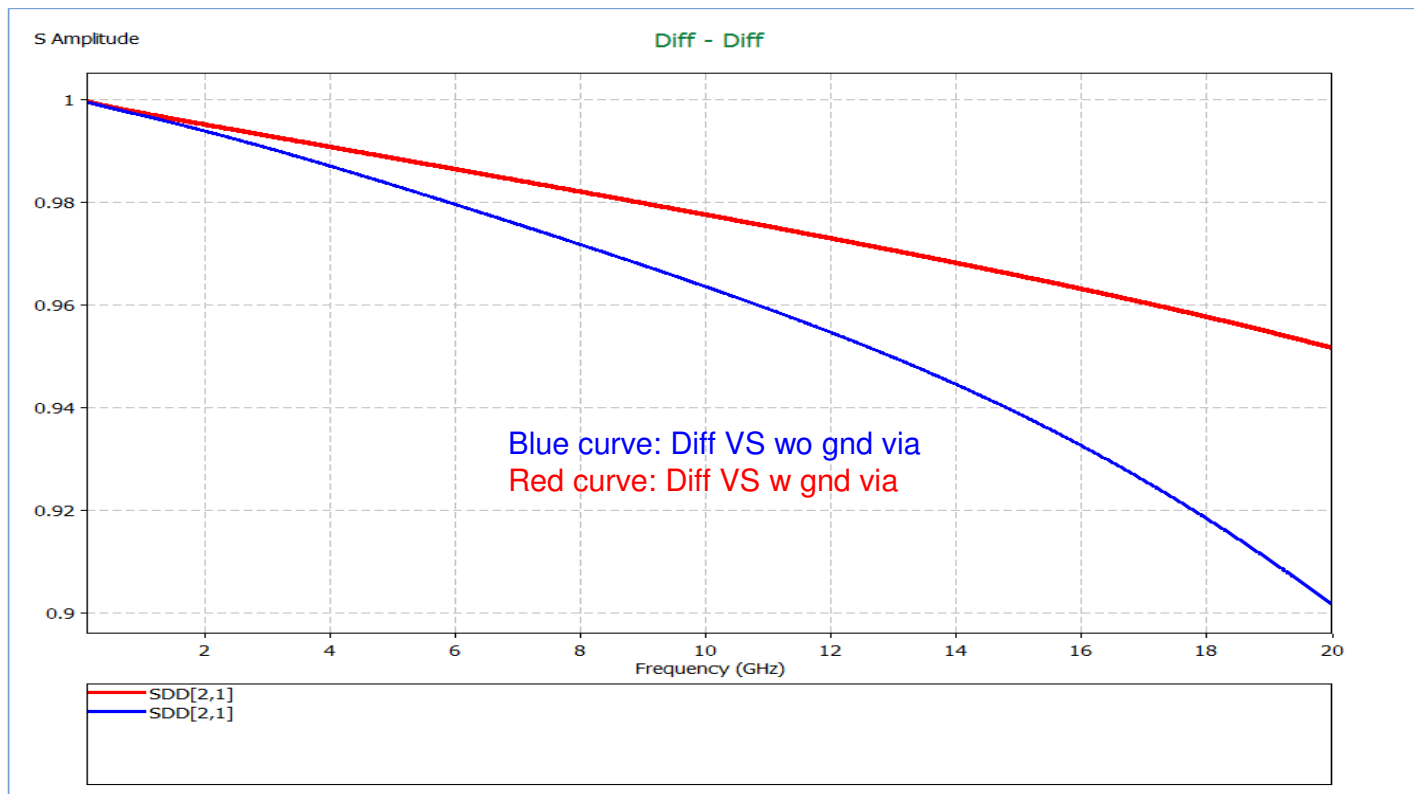
# J Field @1GHz

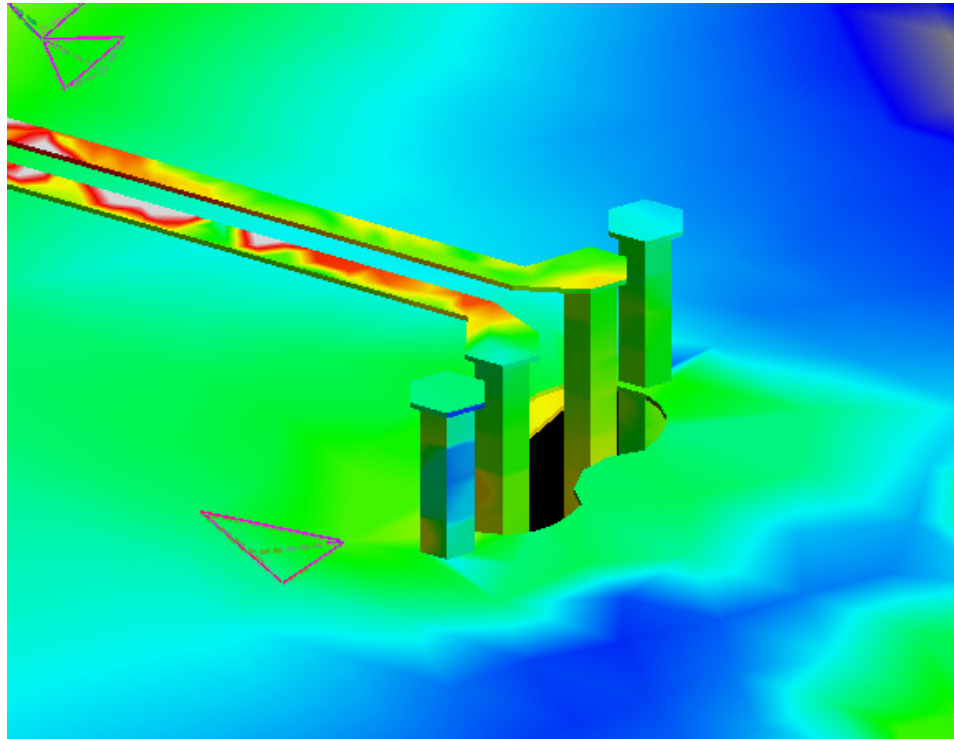


# E Field @



# Differential Insertion Loss







# What to use for via current?

- The cross-sectional area of a via should have at least the same cross-sectional area as the conductor or be larger than the conductor coming into it.

- For plating thickness of 1 mil, the cross-sectional area of a via of size:

- $10\text{mil} = \frac{\pi \cdot 10^2}{4} - \frac{\pi \cdot 8^2}{4} = 28.27\text{mil}^2$
- $12\text{mil} = \frac{\pi \cdot 12^2}{4} - \frac{\pi \cdot 10^2}{4} = 34.56\text{mil}^2$
- $16\text{mil} = \frac{\pi \cdot 16^2}{4} - \frac{\pi \cdot 14^2}{4} = 47.12\text{mil}^2$
- $20\text{mil} = \frac{\pi \cdot 20^2}{4} - \frac{\pi \cdot 18^2}{4} = 59.69\text{mil}^2$
- $30\text{mil} = \frac{\pi \cdot 30^2}{4} - \frac{\pi \cdot 28^2}{4} = 91.11\text{mil}^2$

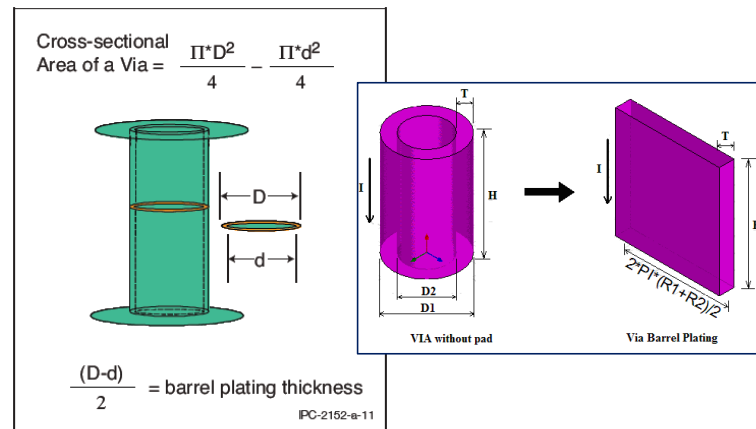


Figure A-11 Via Cross-sectional Area

Courtesy of IPC-2152

# Via current guideline (Chart)

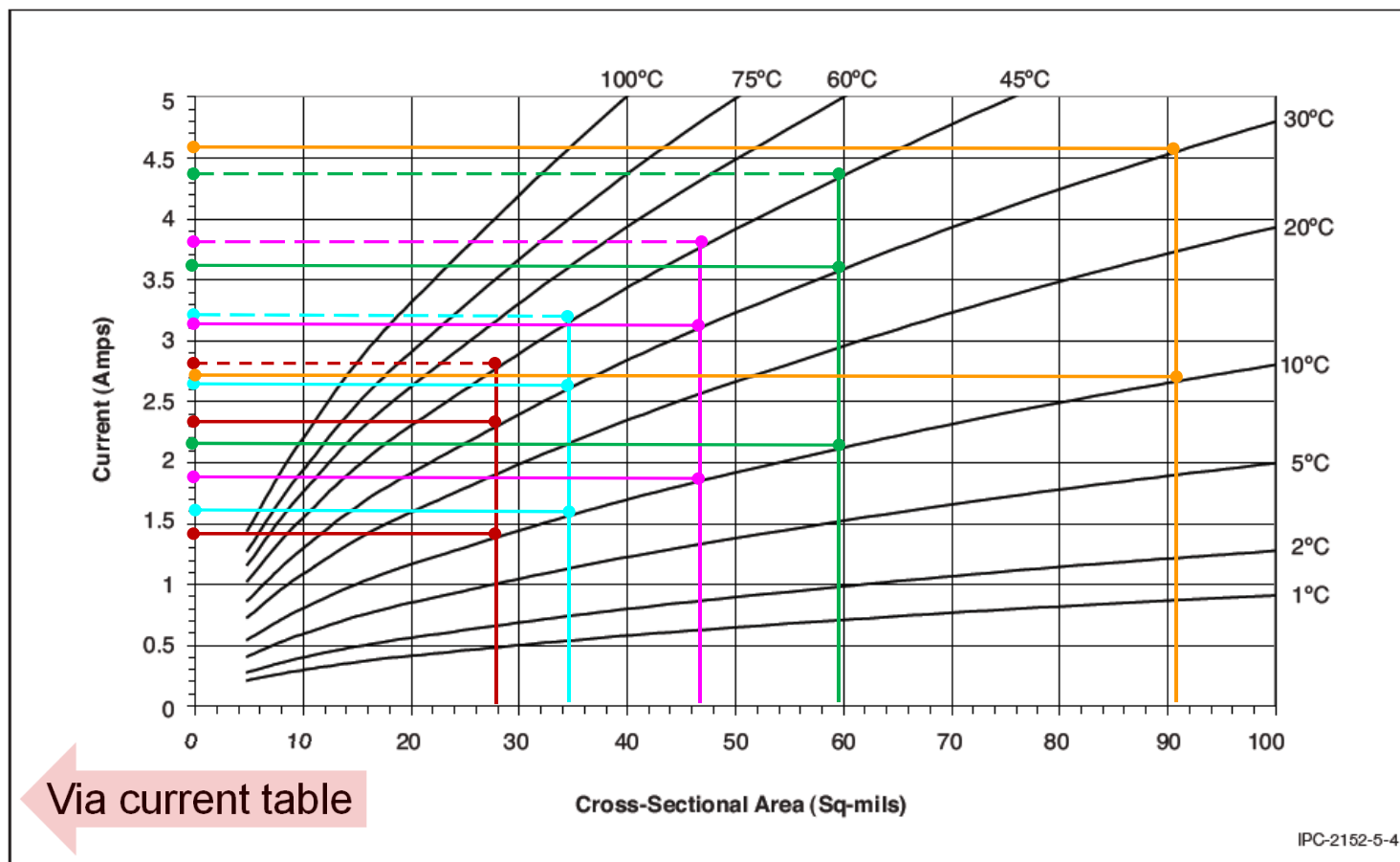


Figure 5-4 Internal and External Conductors (Still Air) (5-100 Sq-mils)

Courtesy of IPC-2152

*epoxy resin based PCB that is 70mil thick, without copper plane layers.*

## Via current guideline (Table)

Via size (mil)	Current for $10^{\circ}\text{C}$ temp rise (A)	Current for $30^{\circ}\text{C}$ temp rise (A)	Current for $45^{\circ}\text{C}$ temp rise (A)
8	1.2	2	2.3
10	1.4	2.3	2.8
12	1.6	2.6	3.2
16	1.8	3.1	3.8
20	2.1	3.6	4.3
30	2.7	4.6	5.7
40	3	5.5	6.8

-67 **Note:** The previous chart represents copper conductors in a polyimide or FR4 epoxy resin based PCB that is 70mil thick, without copper plane layers. If copper planes are present, then temperature rise will be lower.